

# **CHARACTERIZATION OF THE NEUTRON BEAM AT THE RADIATION RESISTANCE TEST FACILITY IN GATCHINA**

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**XXII International Seminar on Interaction of Neutrons with Nuclei  
ISINN-23, 25-29 May 2015, Dubna**

# **ISNP/GNEIS Facility in Gatchina for Neutron Testing with Atmospheric-Like Spectrum**

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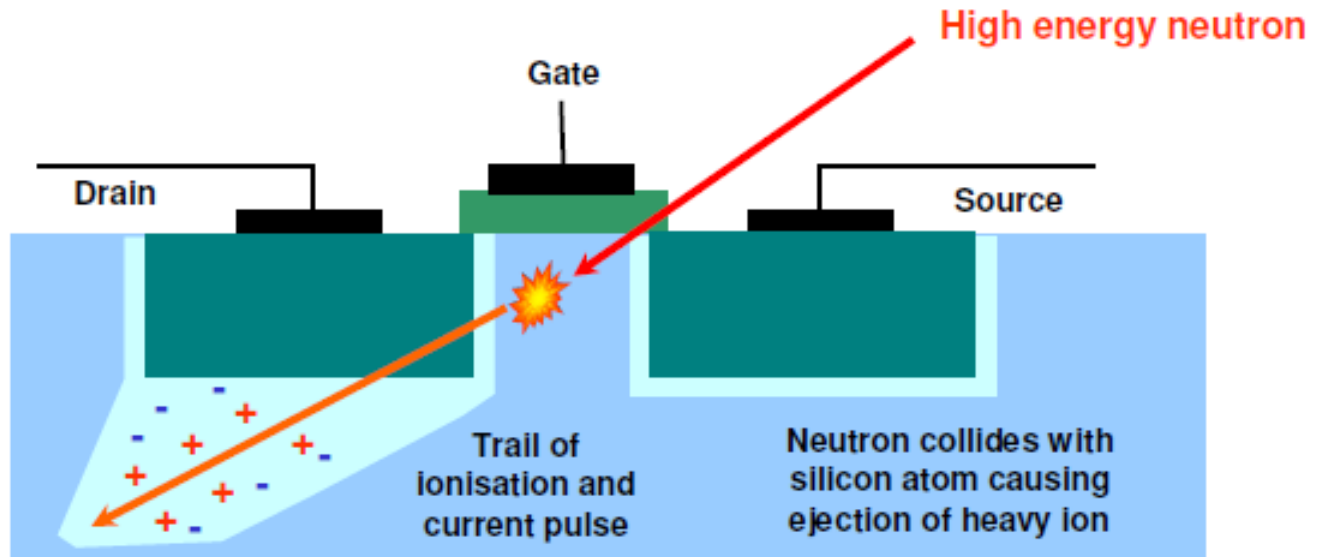
**Institute of Space Device Engineering, Moscow, Russia**

**International Conference**

**Radiation Effects on Components and Systems**

**RADECS-2015, 14-18 September, Moscow**

# NEUTRON-INDUCED SOFT ERROR TESTING of Electronic Components Used for Terrestrial, Avionic and Space Equipment

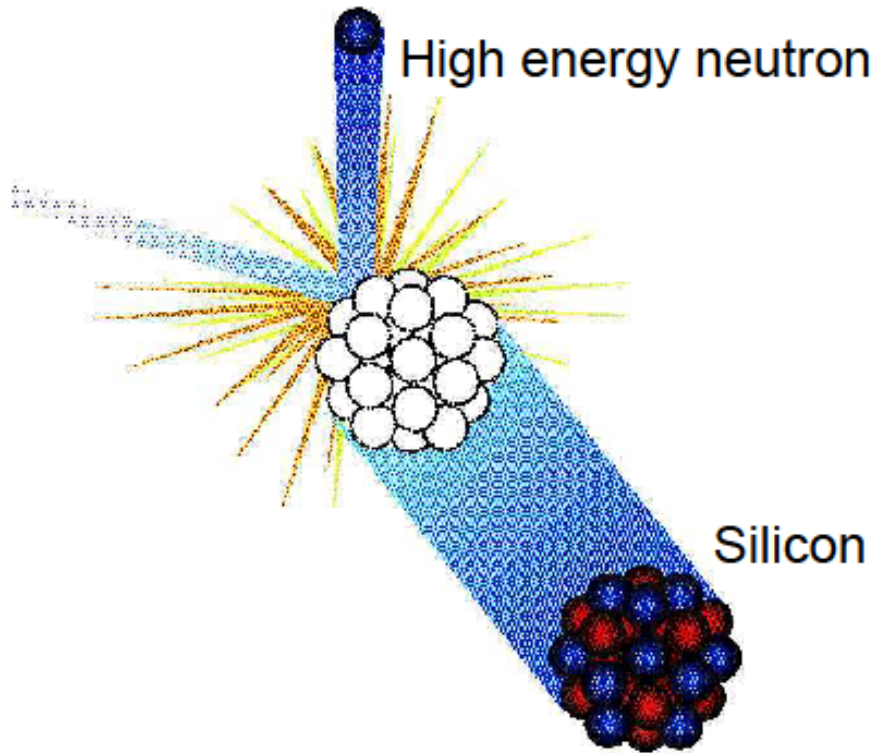


What are **Single Event Effects** and why are they important?

**Single Event Effects** are created when an energetic particle (alpha, neutron, heavy ion) generates enough charge (so-called critical charge) to upset the function of integrated circuit

**Single Event Effect – SEE**

## ELASTIC ENERGY TRANSFER IN SILICON

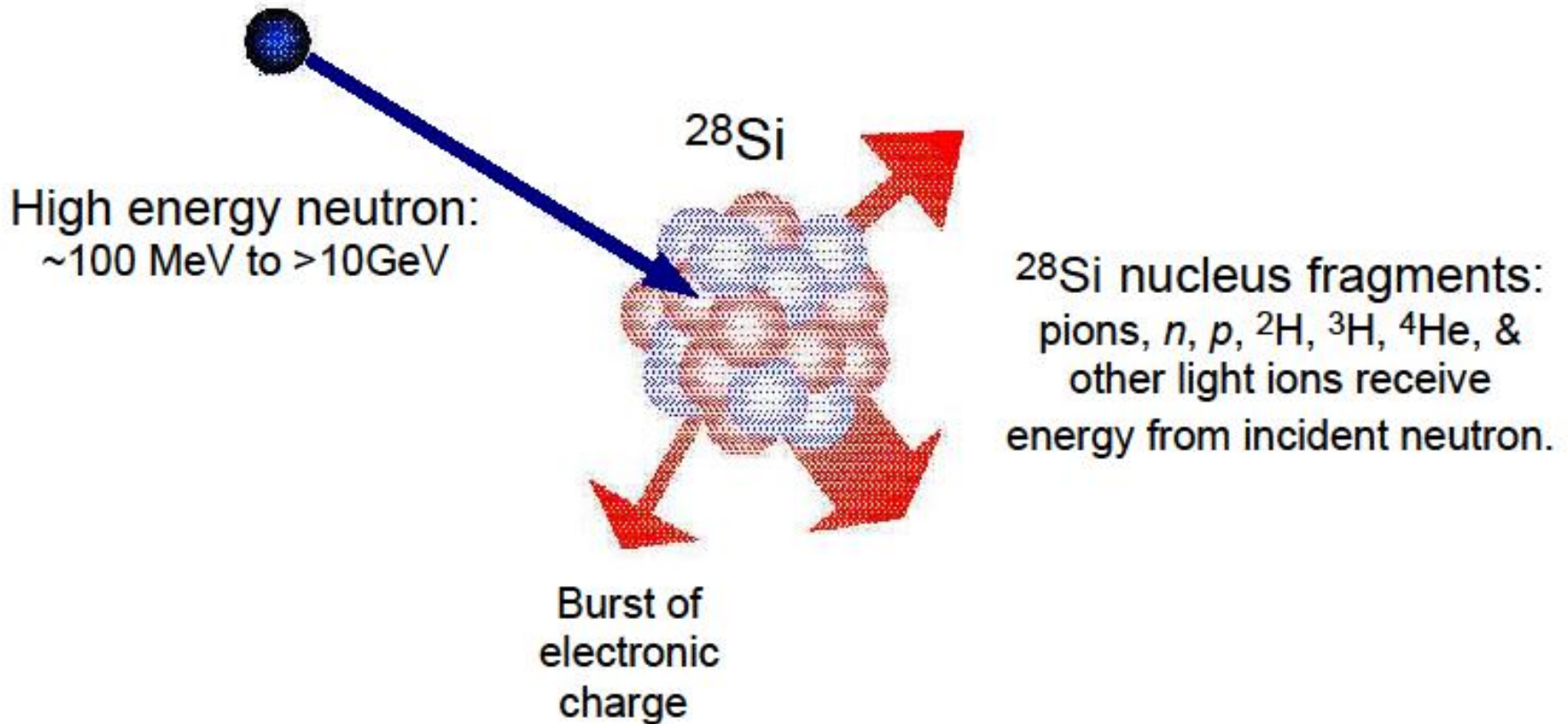


Energy and momentum from cosmic caused neutron can be transferred to a silicon or other IC nucleus.

Maximum recoil energy is 13.3-13.6% of incident neutron. For incident neutron of 100MeV => range up to  $5\mu$  (most  $< 2\mu$ ).



## INELASTIC ENERGY TRANSFER IN SILICON



# ACCELERATED NEUTRON TESTING OF SEE

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- Whole system or component testing of representative equipment to establish the risks and reliabilities
  
- These include:
  - Memory devices
  - Processors
  - Field Programmable Gate Arrays (FPGAs)
  - Solid state power switching
  - Electro-optical devices
  
- Test Requirements:
  - High neutron flux for accelerated testing
  - Atmospheric spectrum

# NEUTRON COMPONENT OF COSMIC RAYS

□ Source of atmospheric neutrons

25km -----

Electromagnetic  
'Soft' Component

11 km -----

Mesonic  
'Hard' Component

Sea Level

Incident Primary  
Cosmic Ray

$\pi^0$

P

N

$\pi^{+/-}$

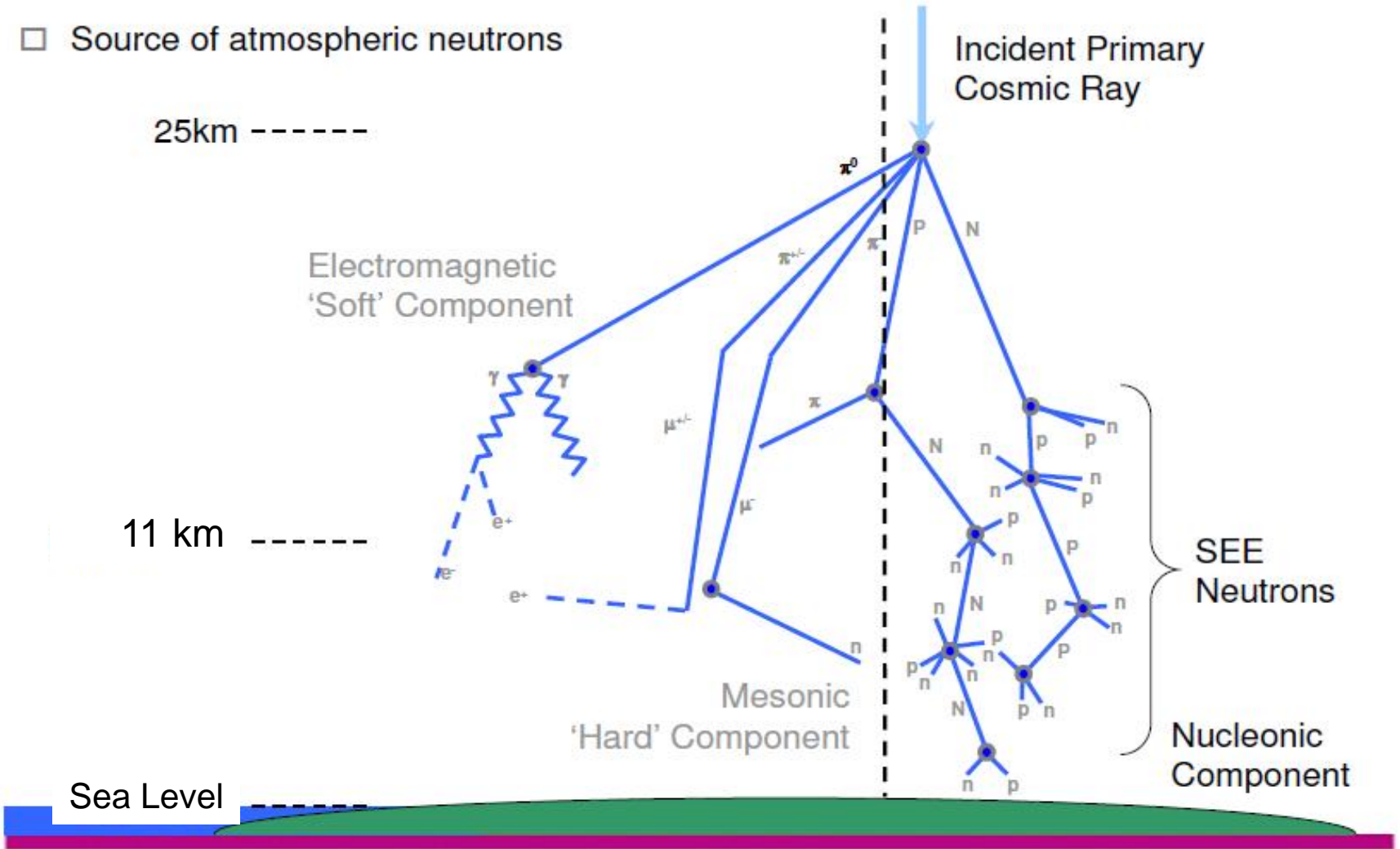
$\pi^-$

$\mu^{+/-}$

$\mu^-$

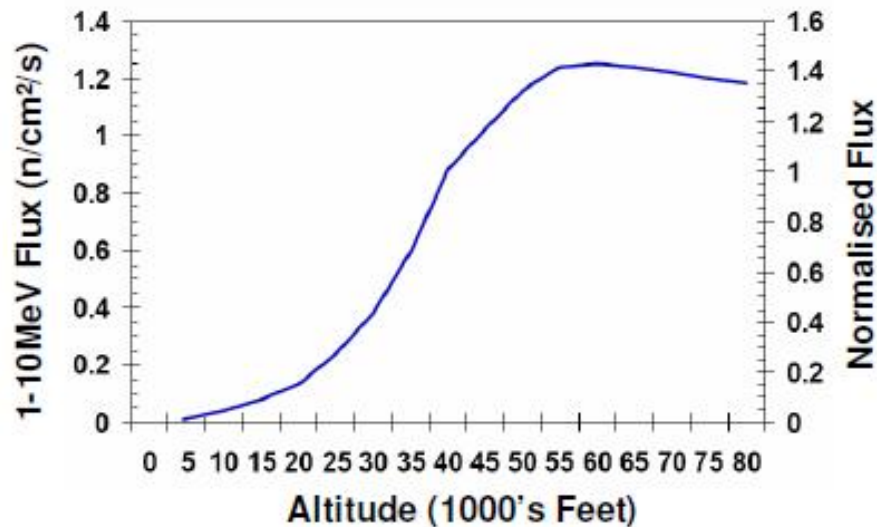
SEE  
Neutrons

Nucleonic  
Component



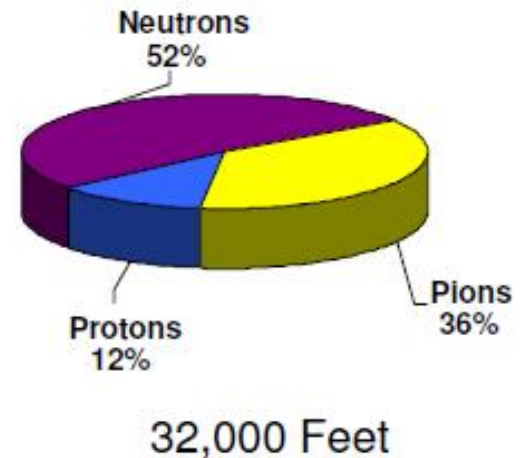
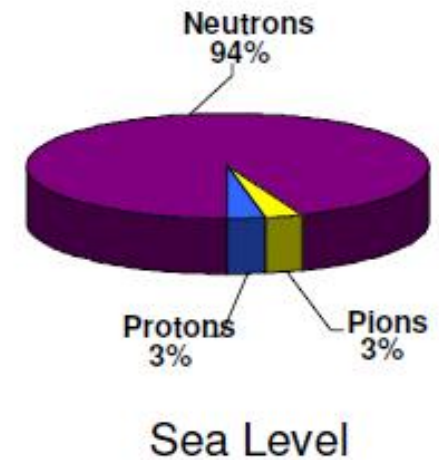
# NEUTRON COMPONENT OF COSMIC RAYS

- Intensity and Composition with Altitude
  - ~ 300x Sea Level at flight altitudes



Source: Boeing Radiation Effects Lab

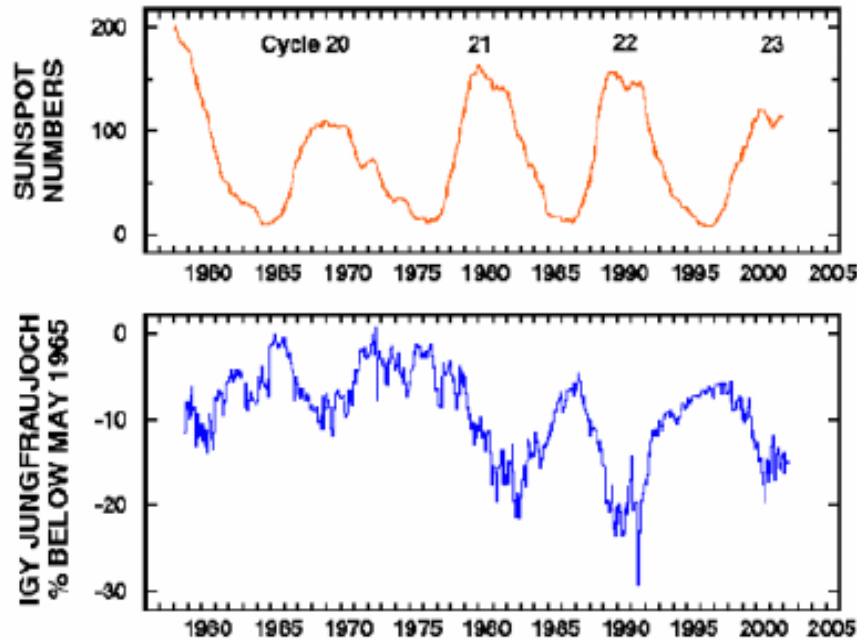
1000 Feet = 304.8 m



Source: JF Zilegler IBM J Res Dev 40, 19-40, (1996)

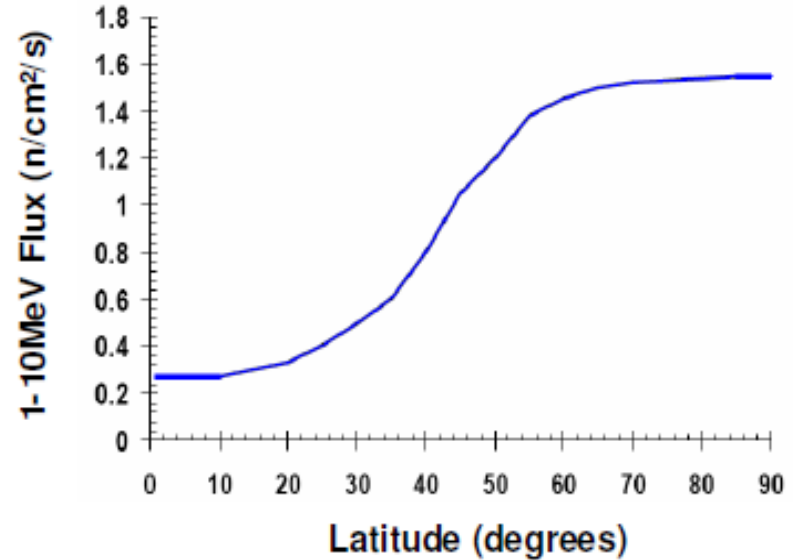
# NEUTRON COMPONENT OF COSMIC RAYS

## □ Intensity with Latitude and Time



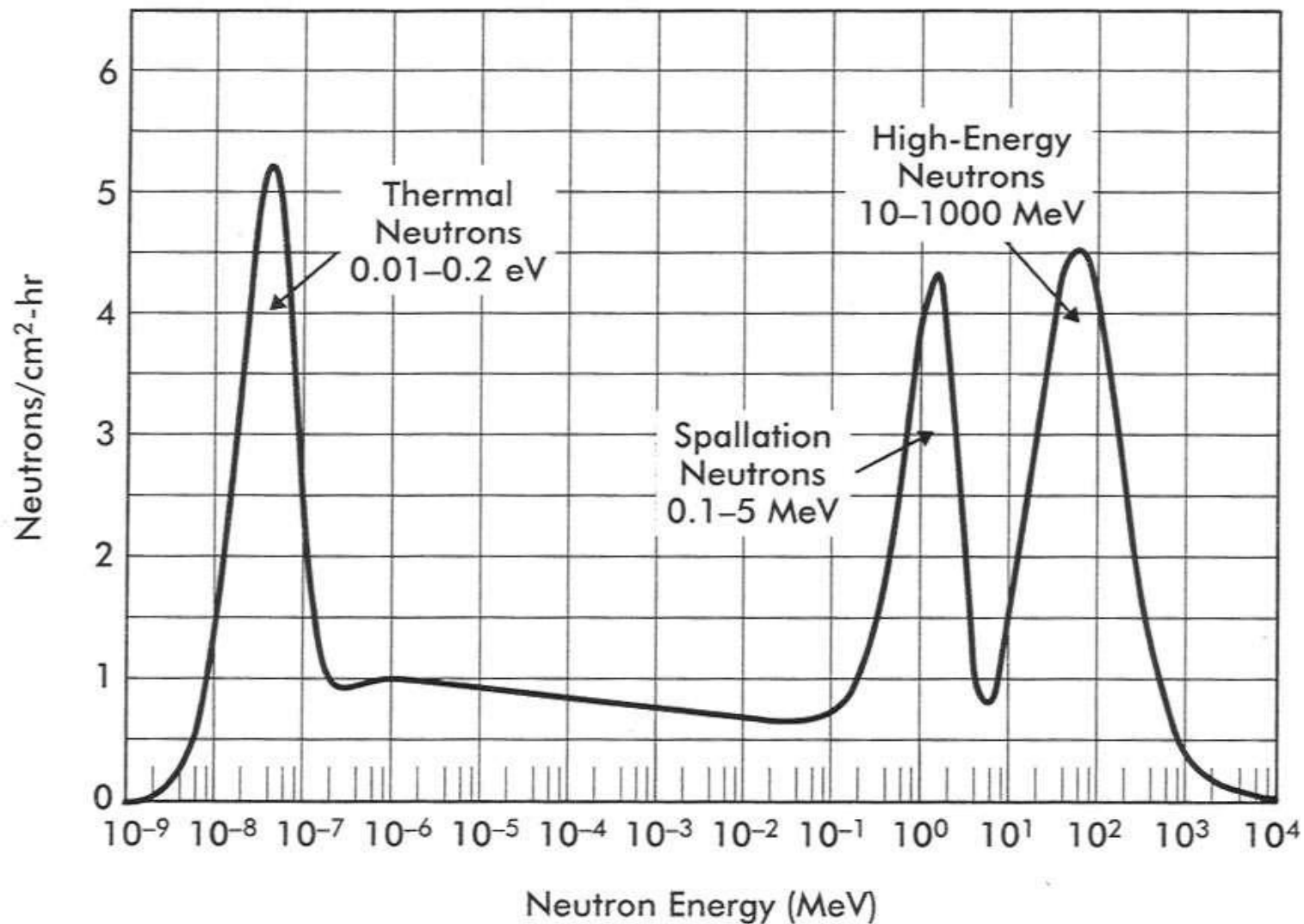
Source: Jungfraujoch neutron monitor data were kindly provided by the Cosmic Ray Group, Physikalisches Institut, University of Bern, Switzerland

Source: Boeing Radiation Effects Lab



Time of Day	<2%
Date in Year	<5%
Solar Cycle	<20%
Lat/Long	400-600%

# TYPICAL SEA LEVEL NEUTRON FLUX





# INTERNATIONAL STANDARD (by JEDEC)

Альянс предприятий электронной промышленности (**Electronics Industries Alliance**), до октября 1997 г. назывался Electronics Industries Association. Профессиональная организация в США, разрабатывающая электрические и функциональные стандарты с идентификатором **RS (Recommended Standards)**. Самый известный из её стандартов - **RS-232C**.

В 1958 году в США Ассоциацией предприятий электронной промышленности был создан Объединённый инженерный совет по электронным устройствам (**Joint Electronic Device Engineering Council - JEDEC**).

В настоящее время JEDEC является мировым лидером по разработке открытых стандартов в микроэлектронной промышленности. JEDEC насчитывает более 3000 членов, представляющих около 300 компаний.

## JEDEC STANDARD

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**Measurement and Reporting of  
Alpha Particles and Terrestrial  
Cosmic Ray-Induced Soft Errors in  
Semiconductor Devices**

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**JESD89**

AUGUST 2001

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JEDEC SOLID STATE TECHNOLOGY ASSOCIATION

**JEDEC**

**EIA**  
Electronic Industries Alliance

# JESD89A (2006)

## STANDARD TERRESTRIAL NEUTRON SPECTRUME

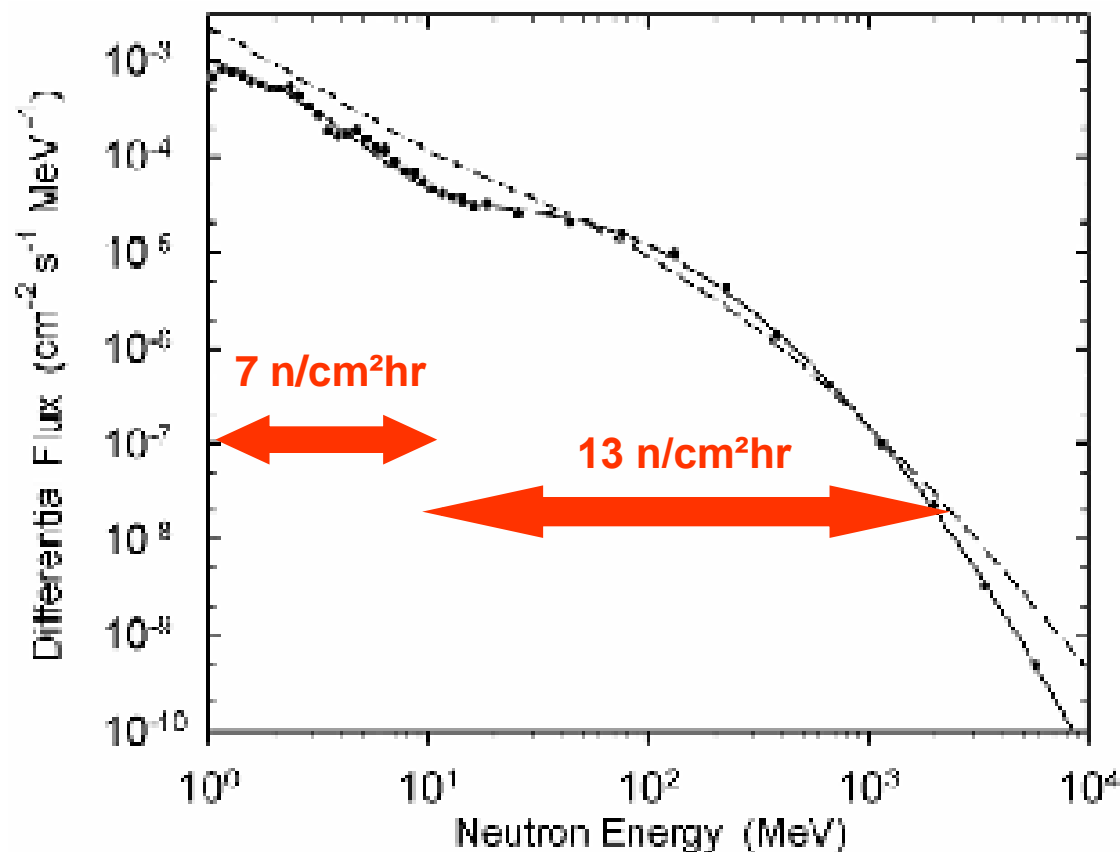


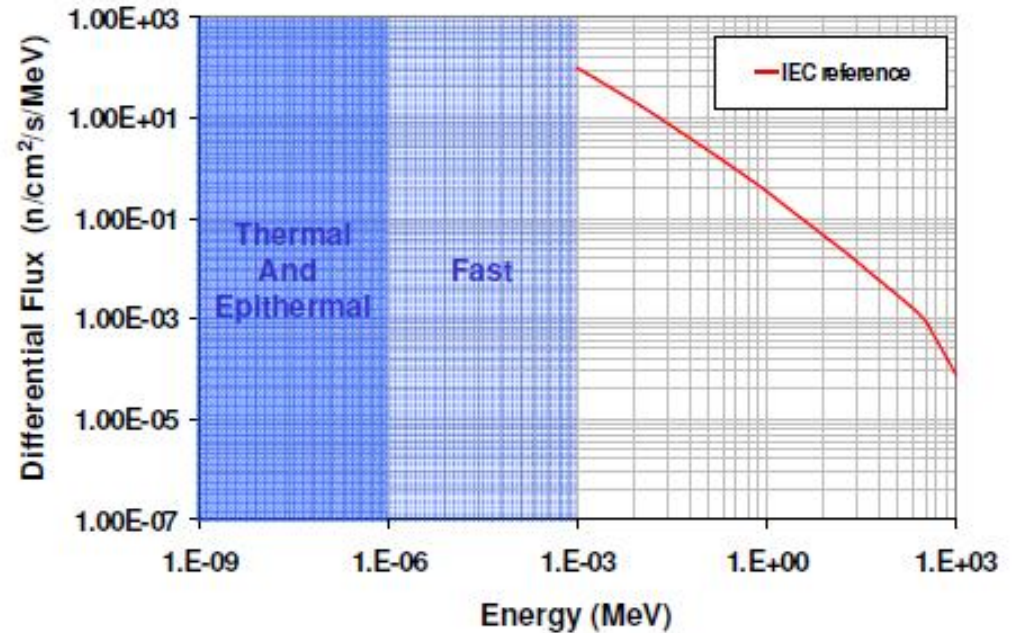
Figure A.2.1 — The differential flux of cosmic-ray-induced neutrons as a function of neutron energy under reference conditions (sea level, New York City, mid-level so activity, outdoors). The data points are the reference spectrum, the solid curve is an analytic fit to the reference spectrum, and the dashed curve is the model from a previous version of this standard, JESD89 (2001).



# INTERNATIONAL STANDARD (by IEC)

## □ Atmospheric Neutron Spectrum for SEE Testing

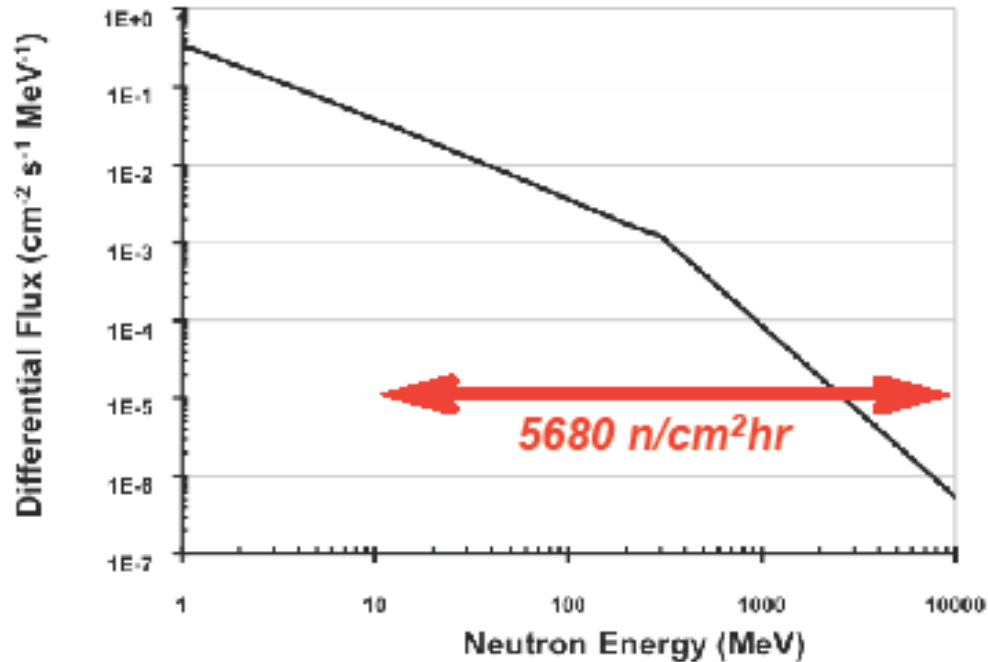
- SEE effects above ~1MeV
- Flux profile is IEC standard
  - International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes international standards for all electrical, electronic and related technologies.



$$\frac{dN}{dE} = 0.346E^{-0.922} \times \exp(-0.0152(\ln E)^2) \quad E < 300 \text{ MeV}$$

$$\frac{dN}{dE} = 340E^{-2.2} \quad E > 300 \text{ MeV}$$

## AVIONIC NEUTRON SPECTRUM AT 12 Km



- “ IEC Technical Specification TS 62396-1 “*Process Management for Avionics - Atmospheric Radiation Effects*”
- “ 400x more intense than terrestrial levels

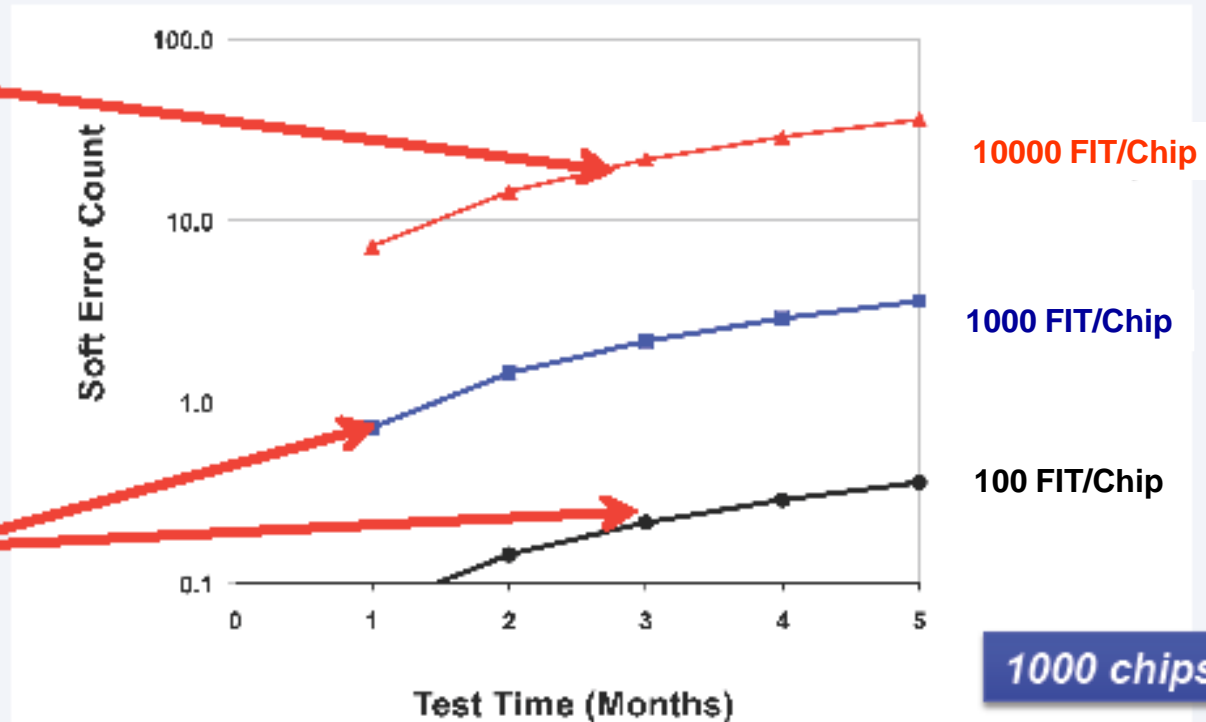
# WHY ACCELERATED NEUTRON TESTING IS NEEDED?

For non-accelerated soft error testing:

$$\text{Fail Count} = (\text{FIT/Chip}) \times (\text{Number of Chips}) \times (\text{Time-hr}) \times 10^{-9}$$

*No significant error count will be observed unless soft error rate is >10,000 FIT/chip*

*For product with < 10,000 FIT/chip soft error rate, data is of limited statistical value*



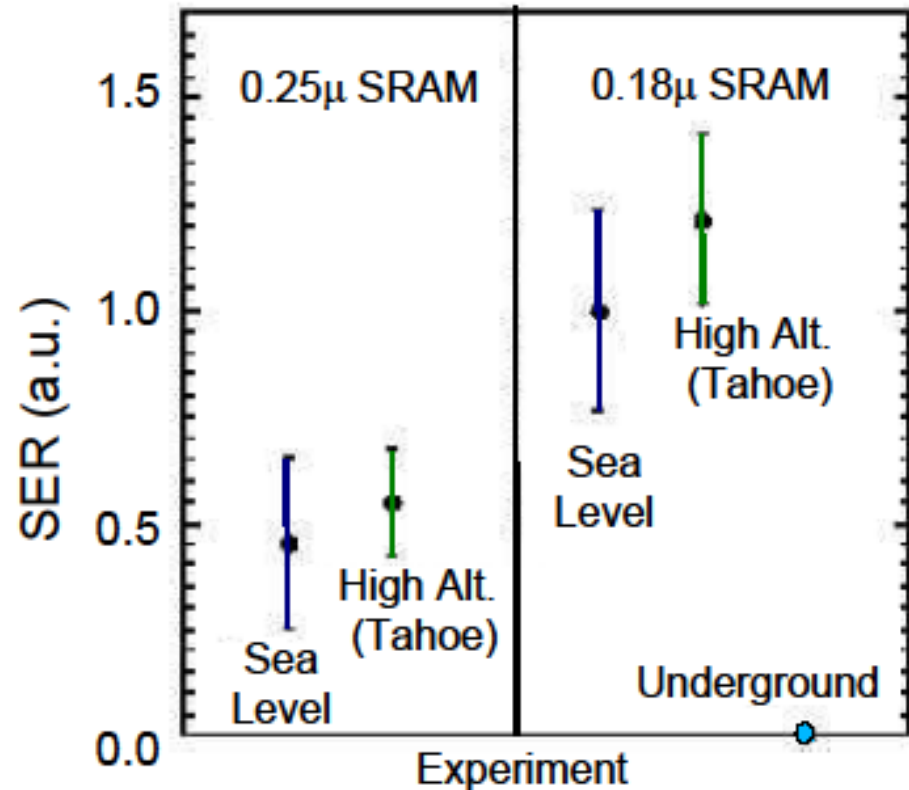
FIT: Failure In Time; 1 FIT is one error in  $10^9$  device-hours.

## HIGH ALTITUDE SOFT ERROR TEST RESULTS

Testing at high altitude allows a 3 to 10x acceleration factor.

Neutron flux increases about 1.3x for each 1000 ft. altitude to >10,000 ft.

Testing can require months and thousands of devices under test.



H. Kobayashi, et. al., Sony [5].

# FACILITIES FOR RADIATION TESTING WITH ATMOSPHERIC – LIKE NEUTRON SPECTRUM

- Los Alamos National Laboratory, New Mexico, USA  
Weapons Neutron Research Facility  
ICE House 'Irradiation of Chips and Electronics'
- Tri-University Meson Facility, Vancouver, Canada  
Neutron Irradiation Facility
- Uppsala University, Sweden  
Theodor Svedberg Laboratory  
ANITA Irradiation facility
- Vesuvio, ISIS at the Rutherford  
Appleton Lab., Oxfordshire, UK  
Neutron Irradiation Facility
- Research Center for Nuclear Physics  
at Osaka University (RCNP), Japan
- Petersburg Nuclear Physics Institute, Gatchina  
ISNP/GNEIS Neutron Irradiation Facility

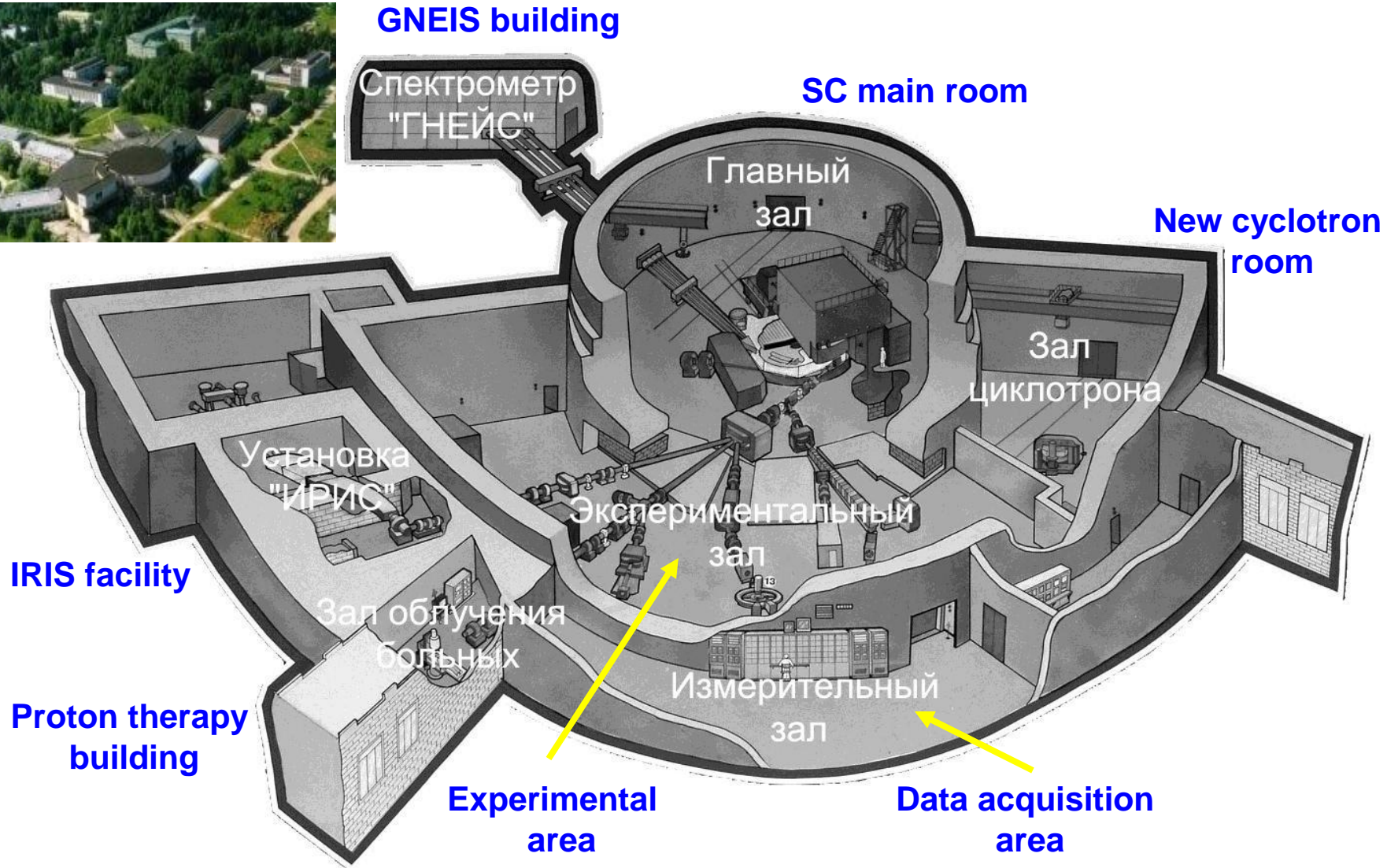


**ROSCOSMOS Test Facilities of the Branch of Joint Stock Company  
 “United Rocket and Space Corporation” -  
 Institute of Space Device Engineering (Moscow)  
 at  
 B.P. Konstantinov Petersburg Nuclear Physics Institute (Gatchina)  
 of the National Research Center “Kurchatov Institute”**

	IS SC - 1000	IS OP - 1000	IS NP - 1000
Conditions	Atmosphere	Atmosphere	Atmosphere
Particles	Protons	Protons	Neutrons
Energy, MeV	1000	200 - 1000	1 - 1000
Flux, particles/cm <sup>2</sup> ·s	10 <sup>5</sup> - 10 <sup>8</sup>	10 <sup>5</sup> - 10 <sup>8</sup>	≤ 4 · 10 <sup>5</sup>
Irradiation area, mm	Ø ≥ 25	Ø ≥ 25	Ø 50 – 100
Uniformity, %	≤ 10	≤ 10	≤ 10
Status	In operation (1998)	In operation (2015)	In operation (2010)



# 1 GeV proton synchrocyclotron of the PNPI (in operation since 1970)

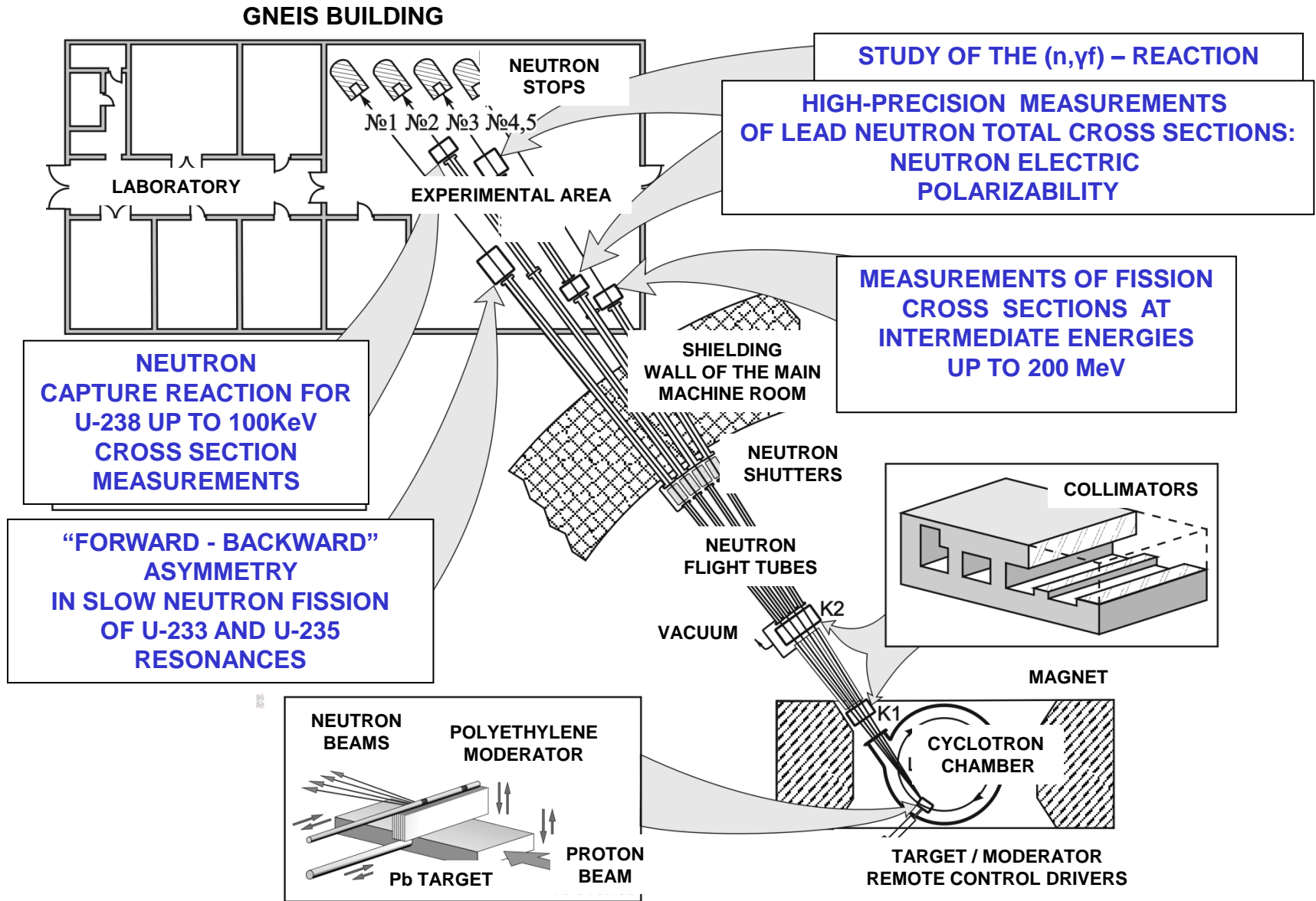


## **Synchrocyclotron SC-1000**

<b>Proton energy</b>	1 GeV
<b>Internal proton beam current</b>	$\leq 3 \mu\text{A}$
<b>Repetition rate</b>	40–60 Hz
<b>Pulsed neutron source</b>	
<b>Average fast neutron intensity</b>	$\leq 3 \cdot 10^{14} \text{ n/s}$
<b>Duration of fast neutron pulse</b>	$\sim 10 \text{ ns}$
<b>Repetition rate</b>	$\leq 50 \text{ Hz}$
<b>Neutron energy range</b>	Thermal – 1000 MeV
<b>Type of neutron spectrum Beam #1-4 (<math>E_n &lt; 0.1 \text{ MeV}</math>)</b>	$1/E^\alpha$ , $\alpha=0.65-0.82$
<b>Type of neutron spectrum Beam #5 (<math>E_n &gt; 0.1 \text{ MeV}</math>)</b>	“spallation”



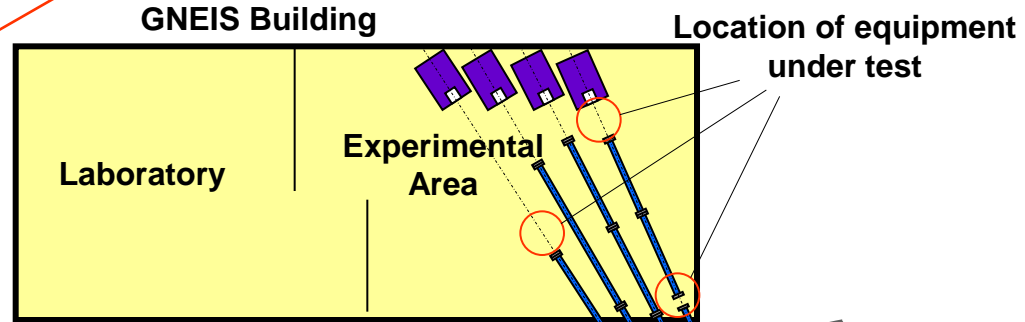
# GNEIS NEUTRON TOF-SPECTROMETER (since 1975)



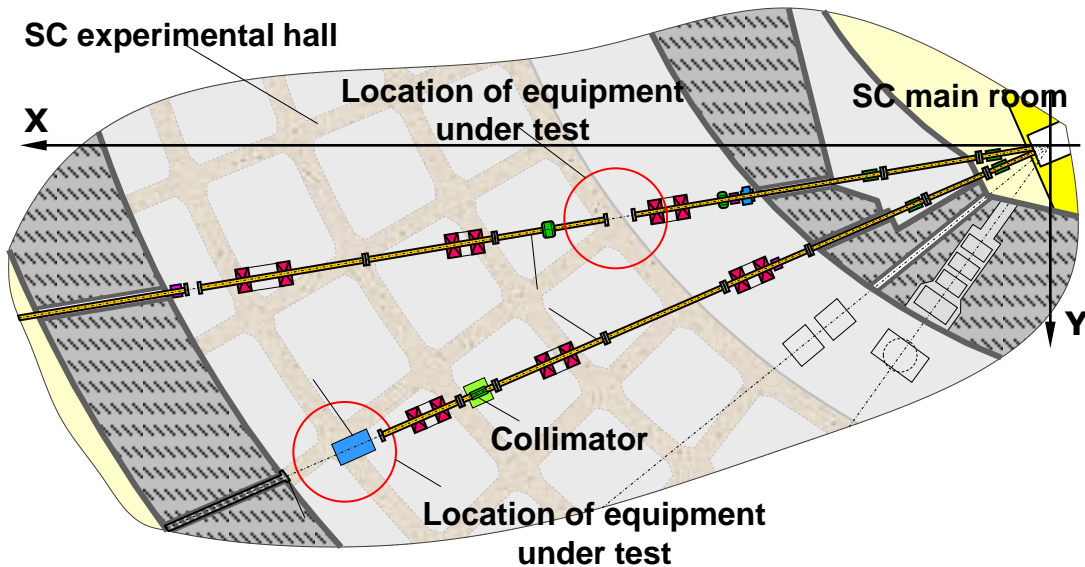
# TESTING OF ELECTRONIC EQUIPMENT AT THE PNPI PROTON AND NEUTRON BEAMS



## Neutron testing site



## Proton testing site



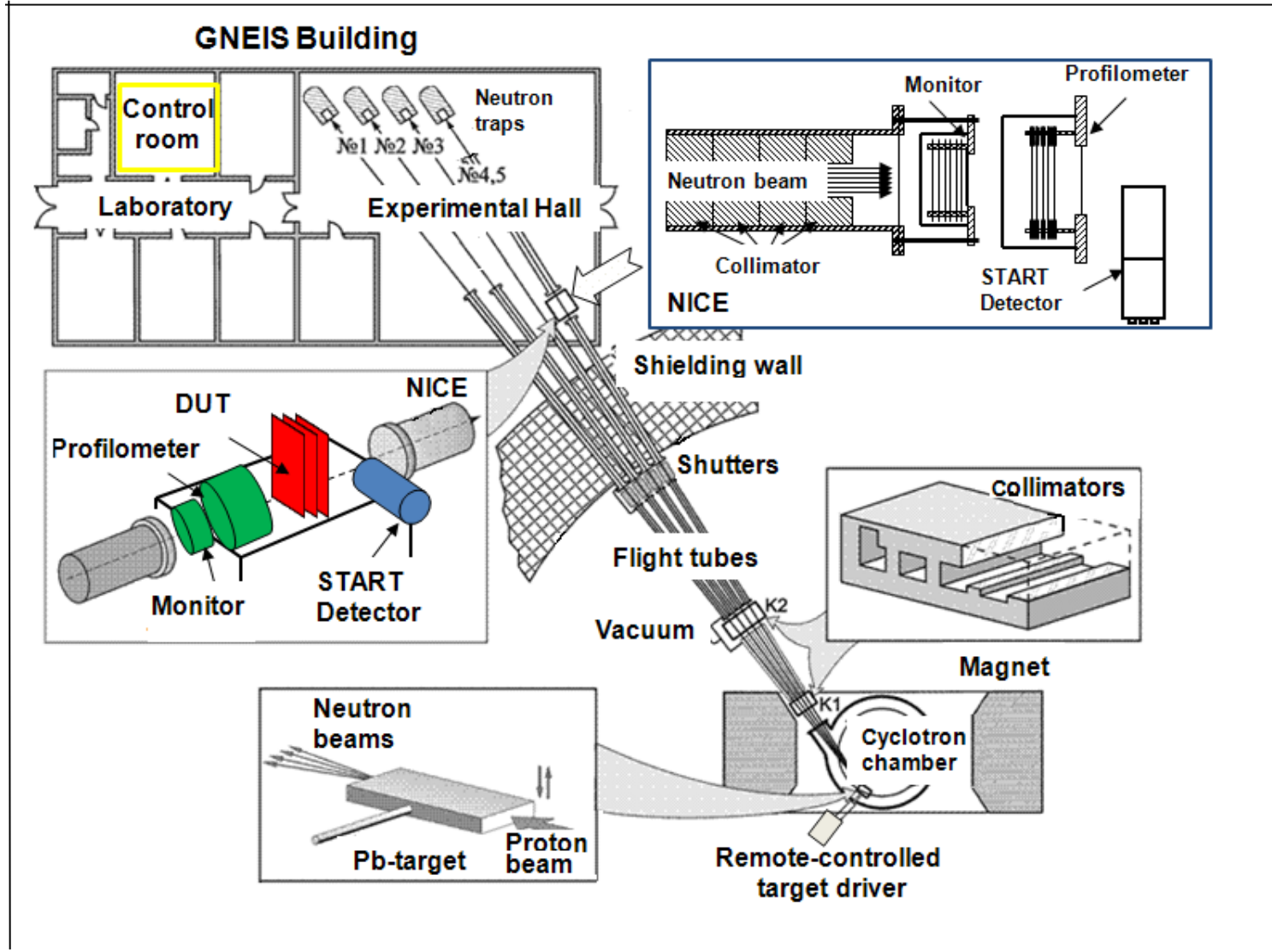
Neutron  
flight  
tubes

SC main  
room

Collimators

Internal neutron-producing  
target

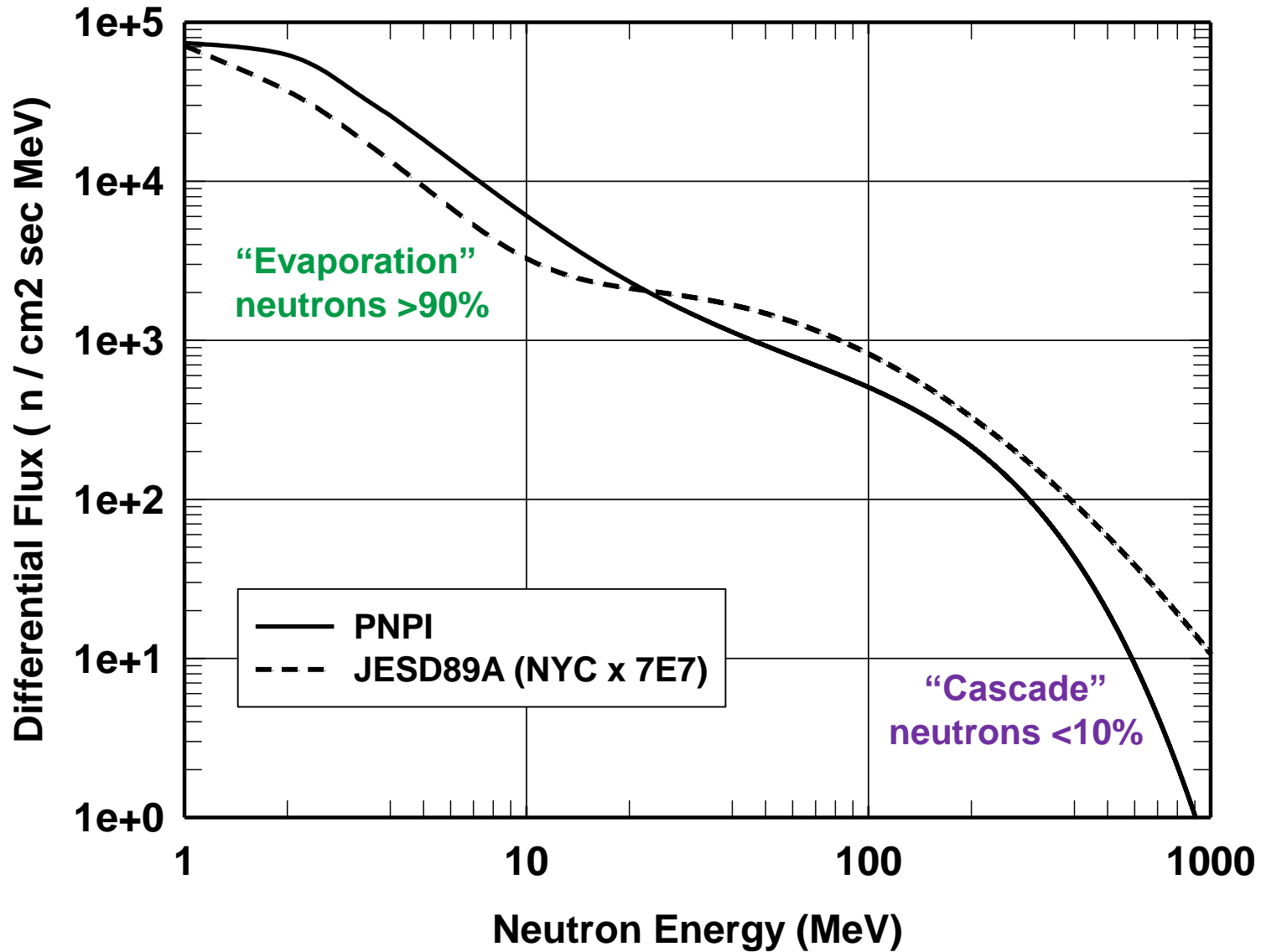
# General View of the GNEIS and NICE Test Facility



**Neutron Irradiation of Chips and Electronics = **NICE** (home nickname!)**

IS NP – official bureaucratic name, direct English transcription of ИСП

# Neutron Energy Spectra of Standard and GNEIS





# How to Compare Various Broad Neutron Spectrum Test Facilities?

## Acceleration Factor - Definition

$$A = \frac{\int_{E_{\min}}^{\infty} \phi_{acc}(E) dE}{\int_{E_{\min}}^{\infty} \phi_{jedec/iec}(E) dE}$$

where  $E_{\min} = 10\text{MeV}$  as specified in JEDEC and IEC

$\phi_{acc}(E)$  - differential neutron flux from the test facility

$\phi_{jedec/iec}(E)$  - differential terrestrial (standard) neutron flux

# Acceleration Factor of Facilities

Facility	JEDEC*) Acceleration Factor	IEC**) Acceleration Factor
ANITA	2.7e8	6.1e5
LANSCCE	1.3e8	2.9e5
TRIUMF	7.6e8	1.7e6
ISIS	1.5e7	3.5e4
RCNP	1.8e8	4.0e5

## Acceleration Factor of NICE/PNPI Facility

**PNPI**

**5.0e7**

**1.2e5**

\*) relative to the sea level

\*\*\*) relative the altitude of 12 km

Exact acceleration factors will vary due to state of tune of the accelerator facilities



## Neutron Soft Error Rate

The neutron soft error rate is

$$R = \int_{E_{\min}}^{\infty} \sigma(E)\phi(E)dE$$

where  $\phi(E)$  is the differential neutron flux and  $\sigma(E)$  is the energy dependent soft error cross sections defined as

$$\sigma(E) = \frac{\text{Number of Soft Error Events}}{\phi(E)T}$$

and T is time



# Theoretical Weibull Approximation of Cross-section

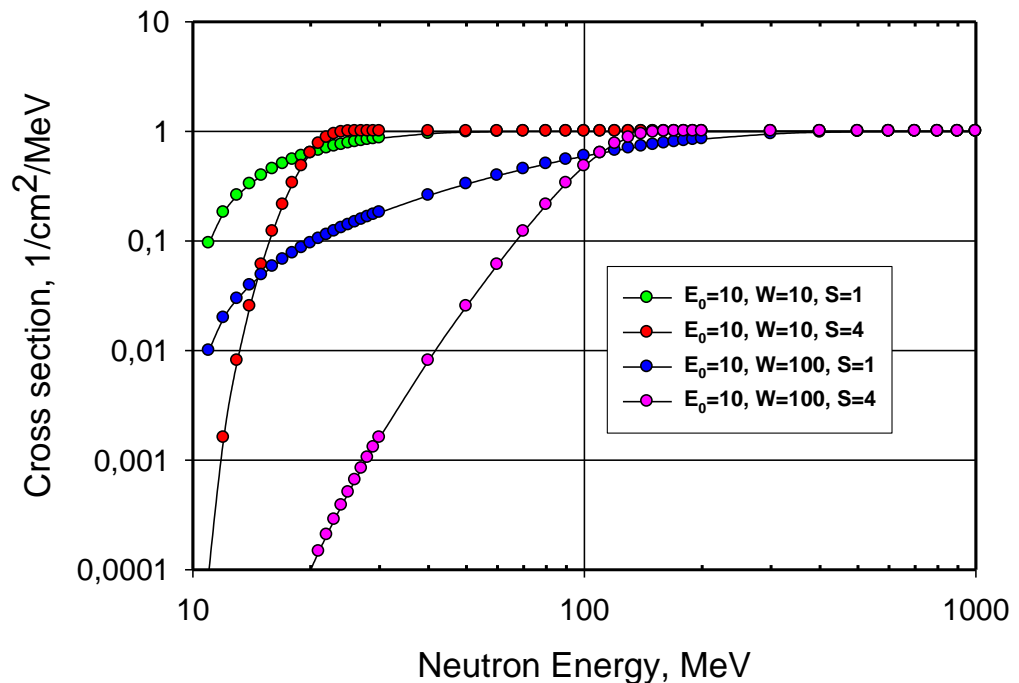
$$\sigma(E) = \sigma_L \left( 1 - e^{-\left[ \frac{E - E_0}{W} \right]^S} \right)$$

where  $\sigma_L$  - asymptotic high energy cross section

$E_0$  - cut-off energy (i.e. no upsets below  $E_0$ )

$W$  - "width" parameter

$S$  - "shape" parameter



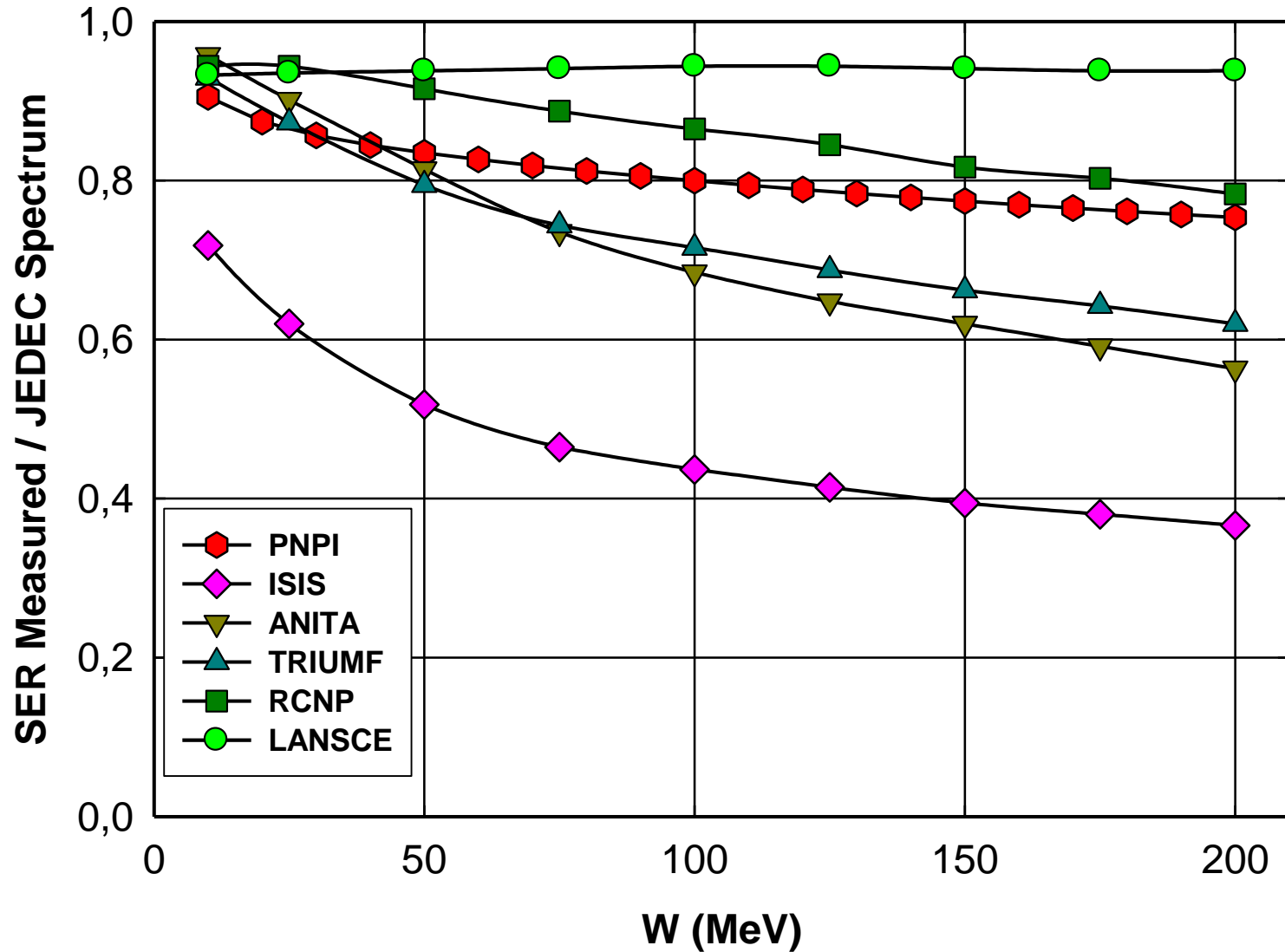
# Error Ratio – Due to Mismatch of Beam Facility and Real Neutron Spectra

$$\text{ErrorRatio} = \frac{R_{\text{measured}}}{AR_{\text{jedeclic}}} = \frac{\int_{E_{\min}}^{\infty} \sigma(E) \phi_{\text{acc}}(E) dE}{A \int_{E_{\min}}^{\infty} \sigma(E) \phi_{\text{jedeclic}}(E) dE}$$

- Error Ratio < 1 Accelerated measurement is under-predicting SER
- Error Ratio = 1 Accelerated measurement is correct
- Error Ratio > 1 Accelerated measurement is over predicting SER

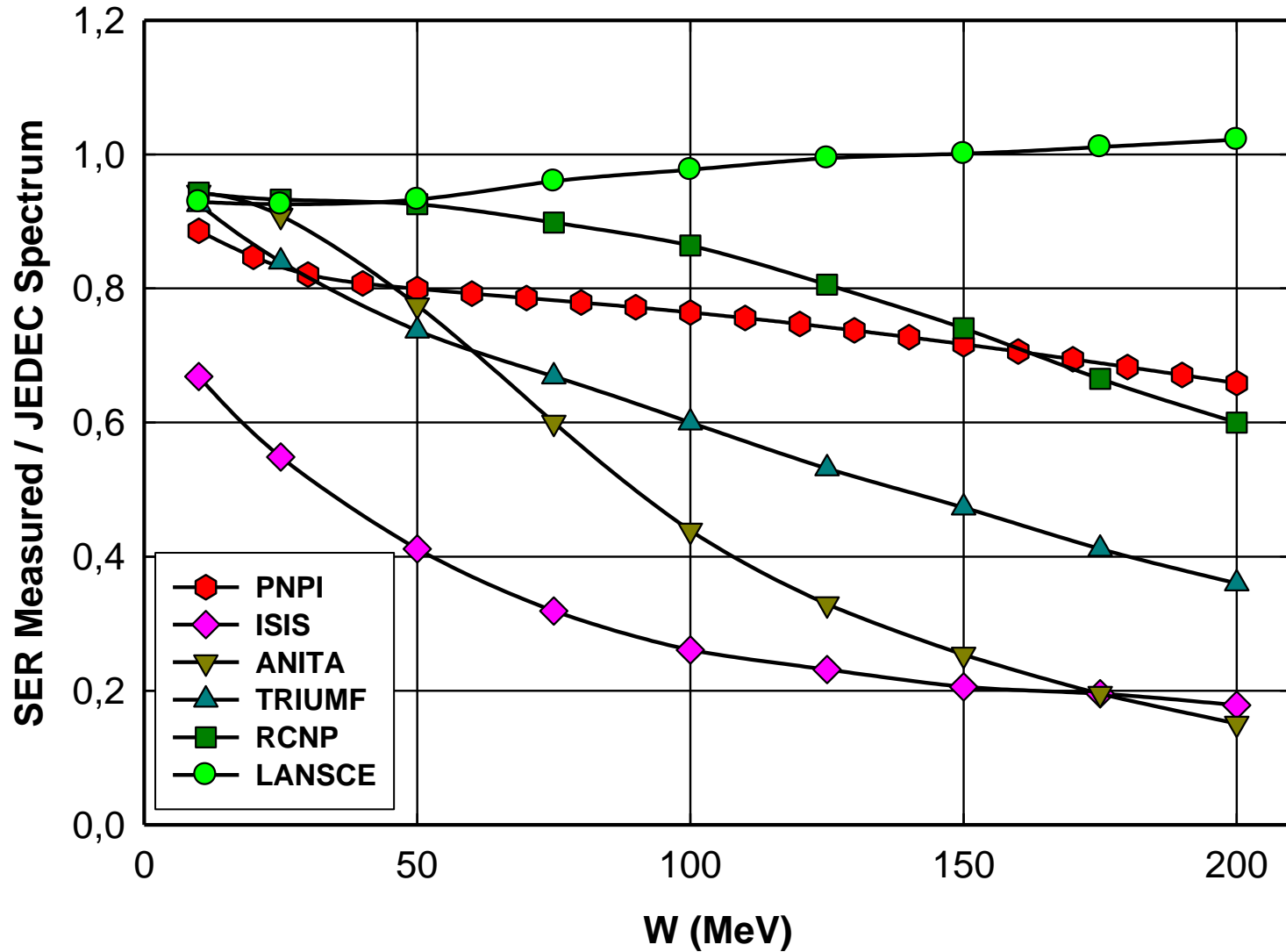
# Error in SER estimate as a function of W

for  $E_0 = 10$  MeV and  $S = 1$  (devices with low critical charge)



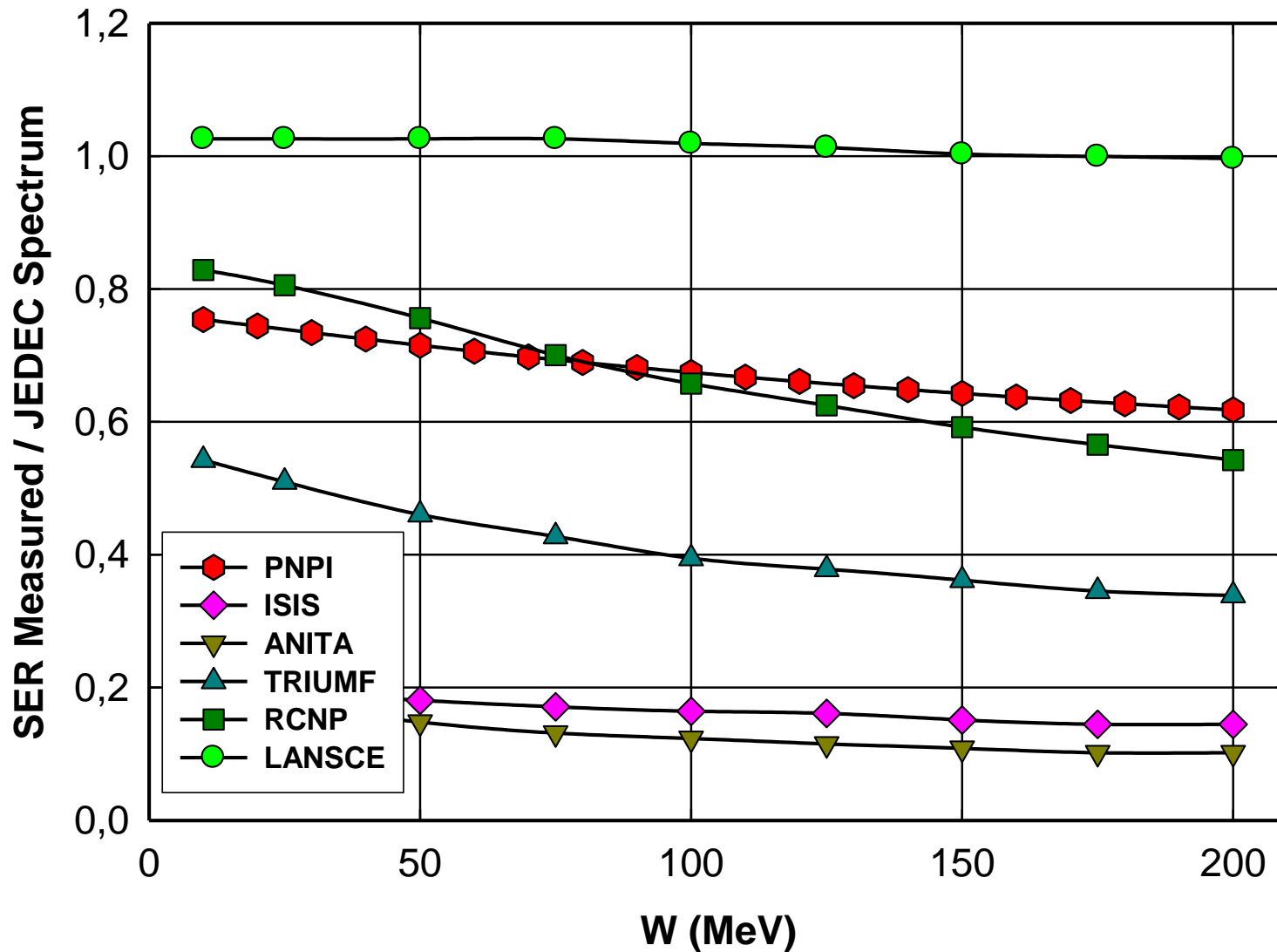
# Error in SER estimate as a function of W

for  $E_0 = 10$  MeV and  $S = 4$  (devices with low critical charge)



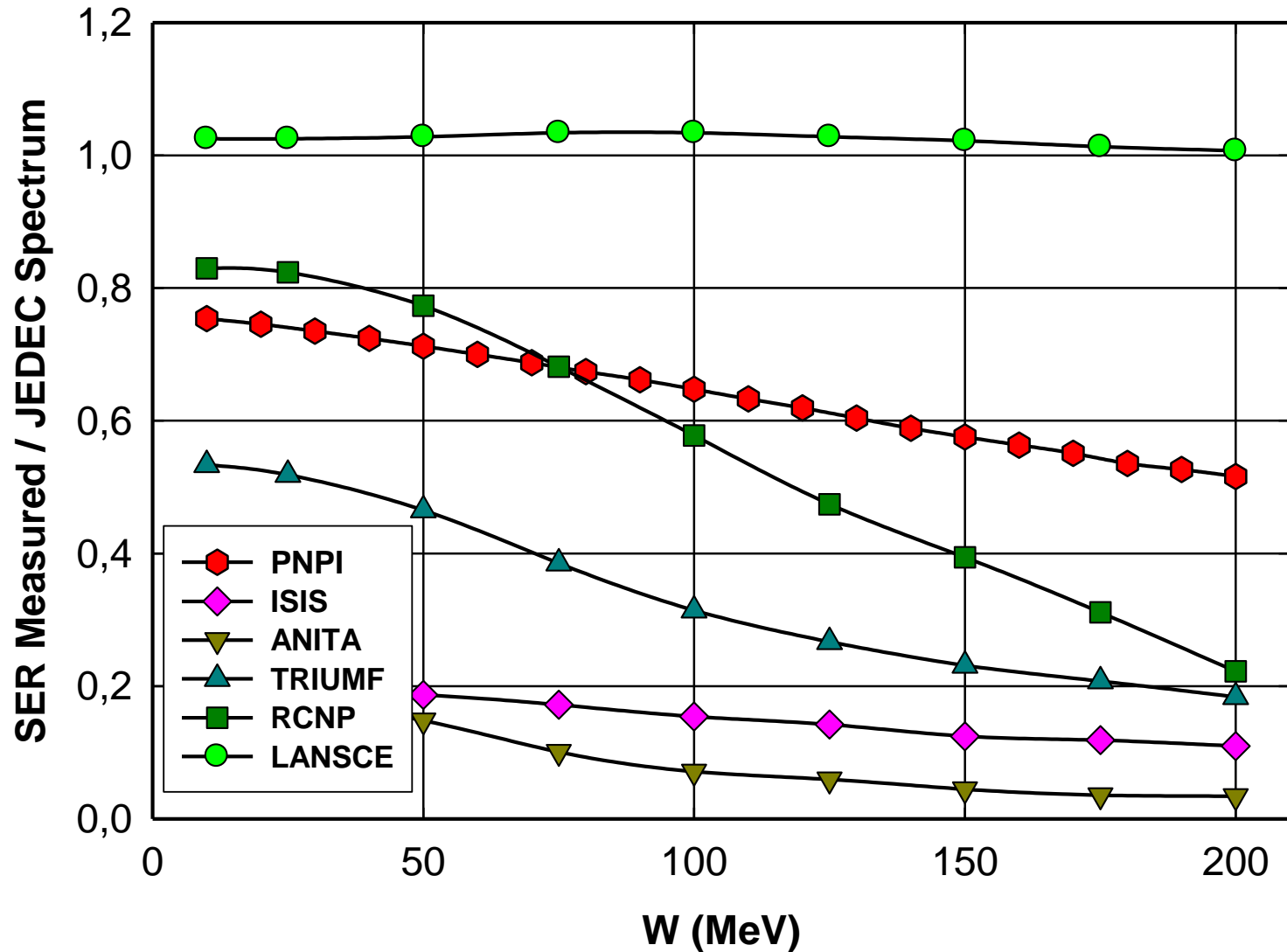
# Error in SER estimate as a function of W

for  $E_0 = 100$  MeV and  $S = 1$  (devices with large critical charge)



# Error in SER estimate as a function of W

for  $E_0 = 100$  MeV and  $S = 4$  (devices with large critical charge)



# Devices Used at the PNPI Test facility for Characterization of the Neutron Beam

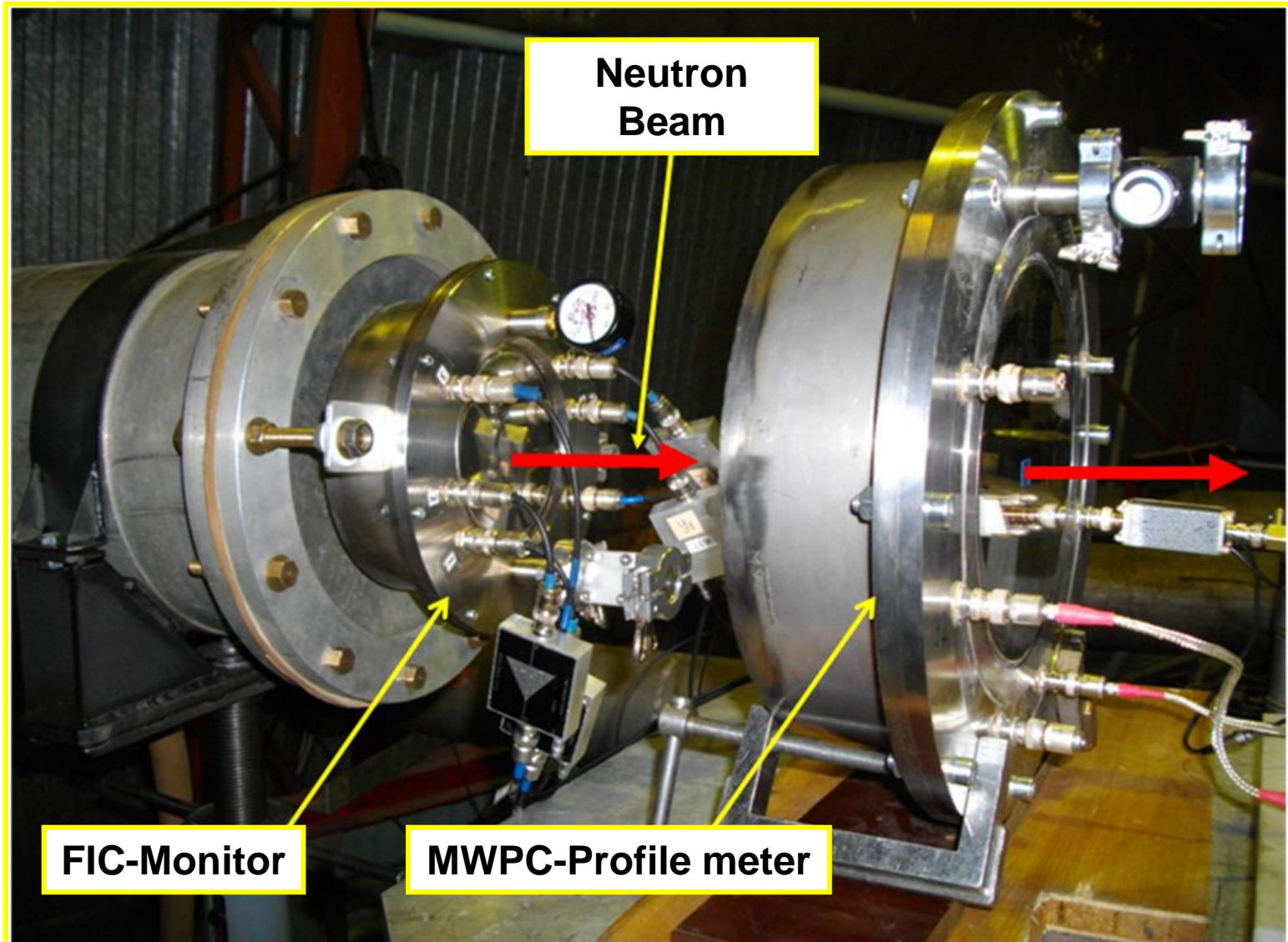
## Monitor: Fission Ionization Chamber (FIC)

- differential neutron flux (energy spectrum),  $\Phi(E)$ , n/cm<sup>2</sup>·sec·MeV
- integral neutron flux,  $I = \int \Phi(E)dE$ , n/cm<sup>2</sup>·sec
- neutron fluence,  $T \cdot I$ , n/cm<sup>2</sup>

## Profilometer: Multiwire Proportional Counter (MWPC)

- 2D-distribution of neutron flux,  $I(X, Y)$ , over beam cross section
- center of gravity of the beam cross section
- uniformity of the beam cross section
- “effective” width of the beam cross section along X,Y-axes

# Devices Used at the PNPI Test facility for Characterization of the Neutron Beam



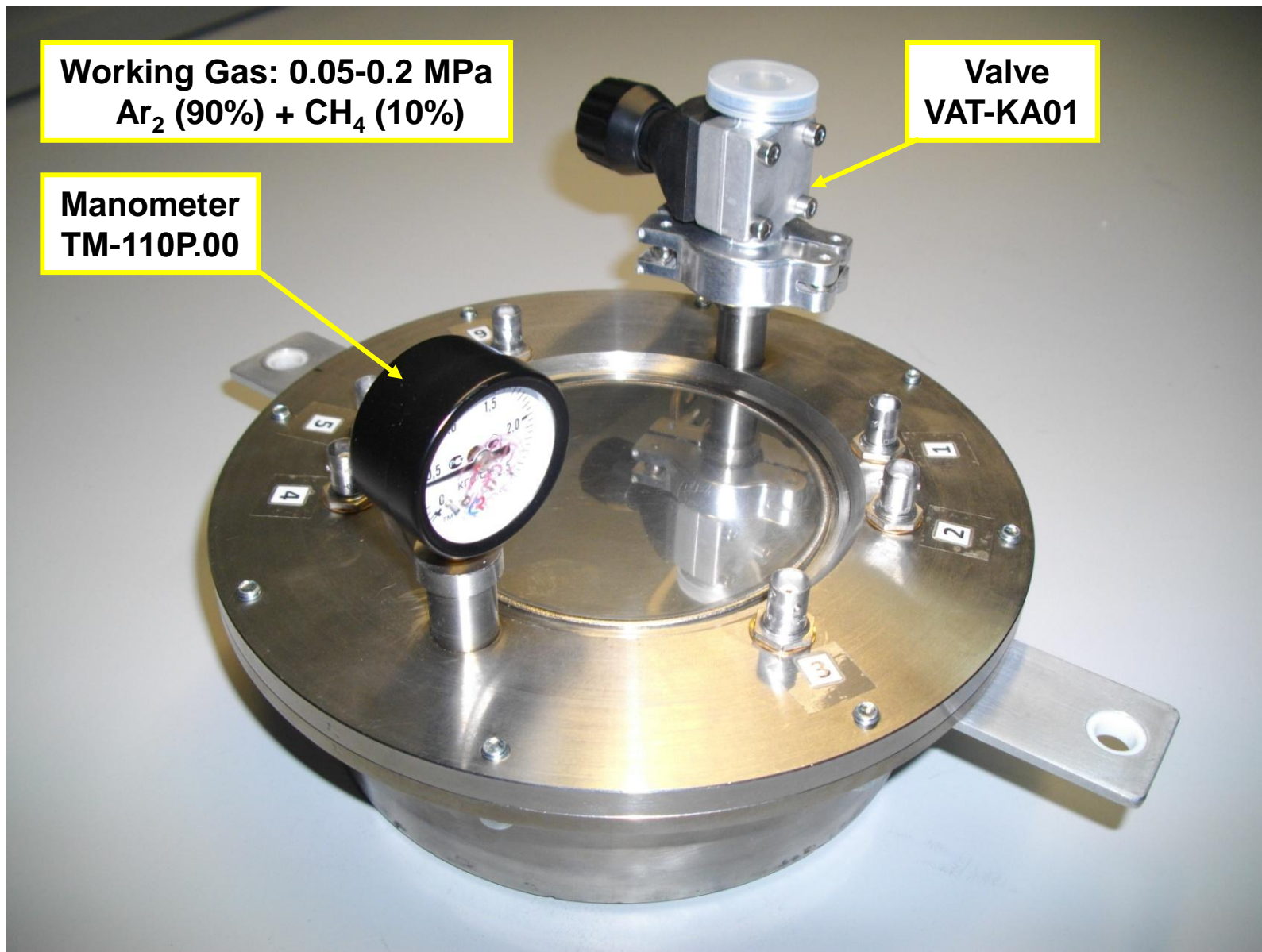


# Neutron Beam Monitor - Fission Ionization Chamber (FIC) with U-235 and U-238 targets

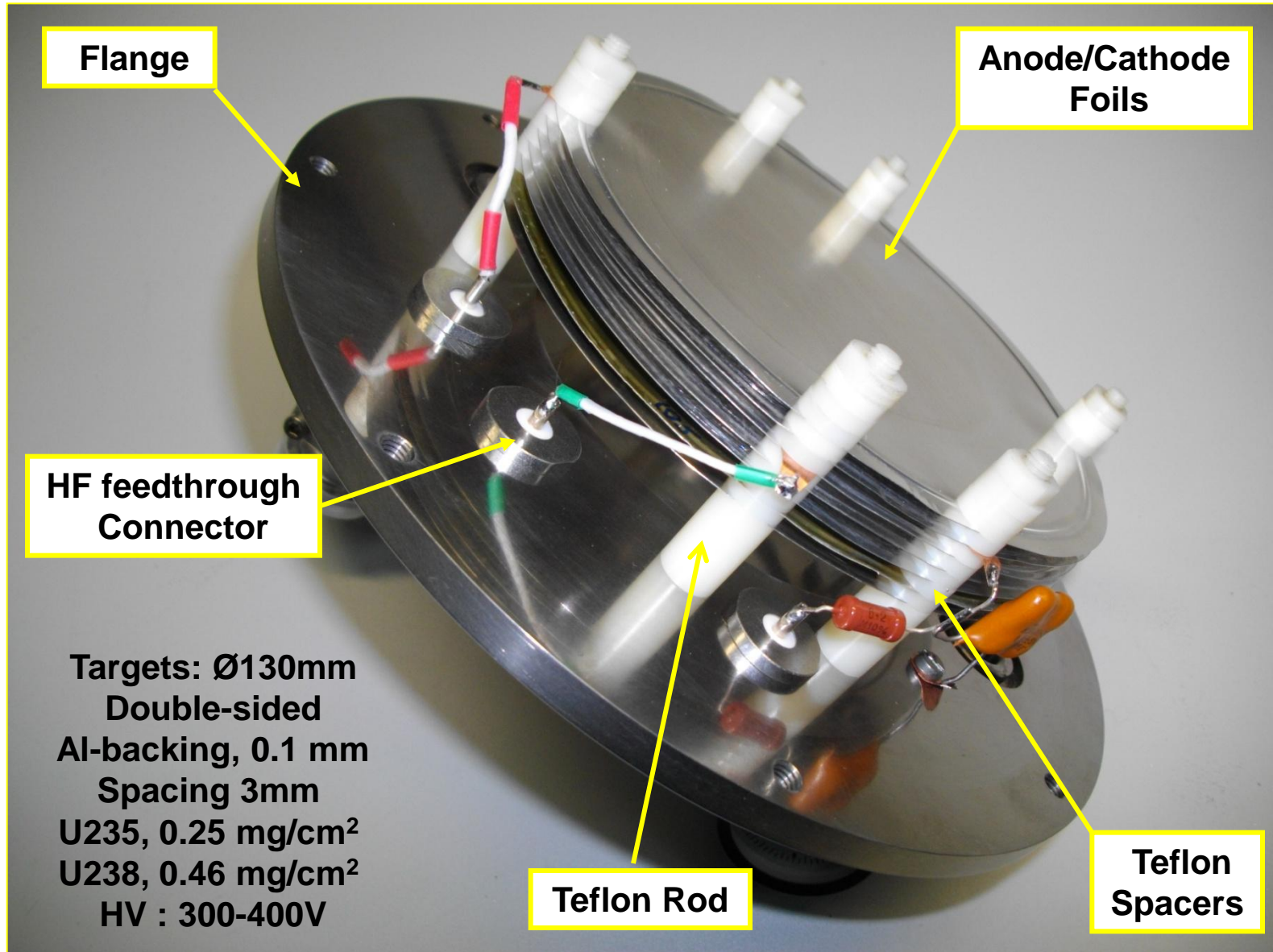
Working Gas: 0.05-0.2 MPa  
Ar<sub>2</sub> (90%) + CH<sub>4</sub> (10%)

Manometer  
TM-110P.00

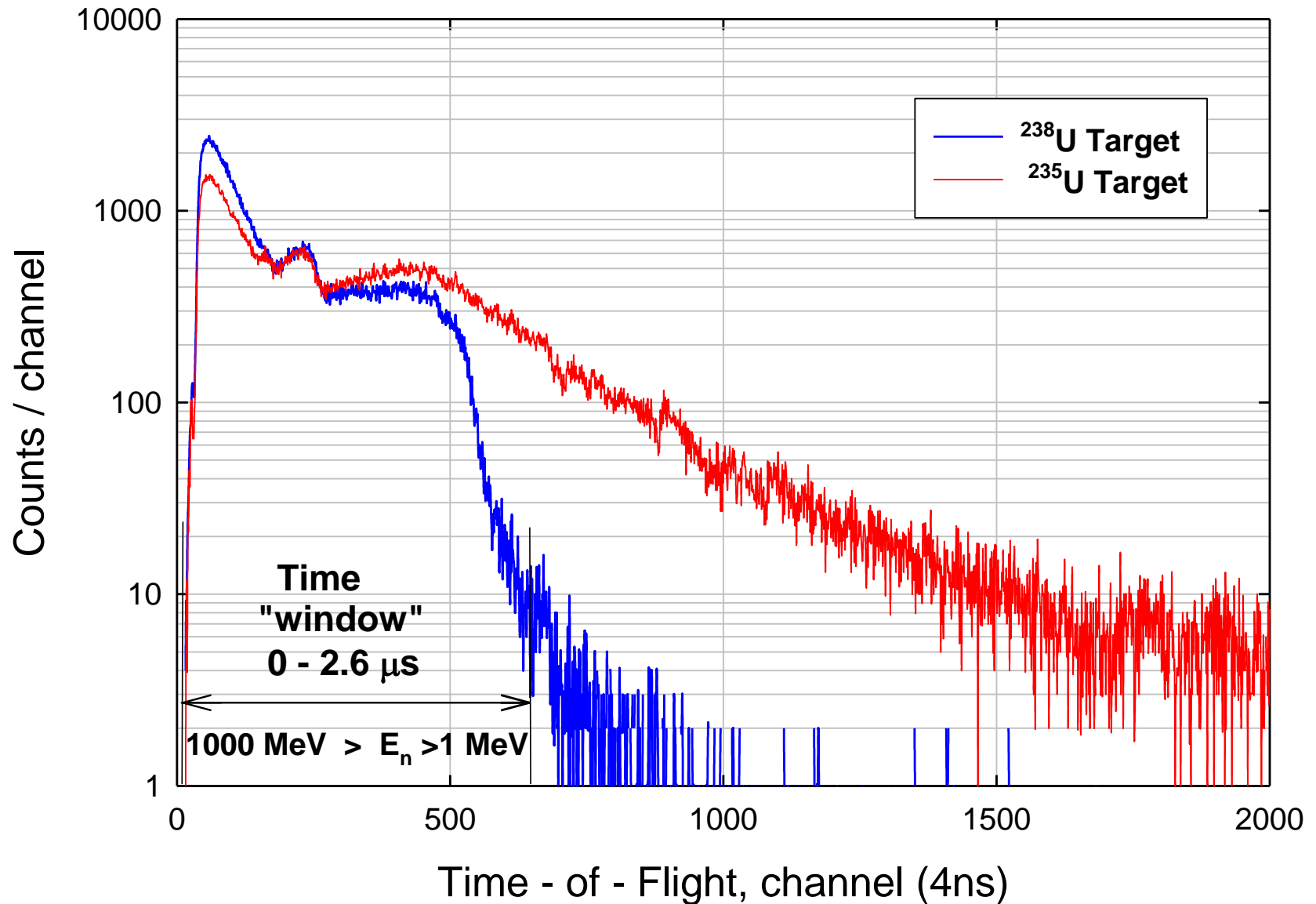
Valve  
VAT-KA01



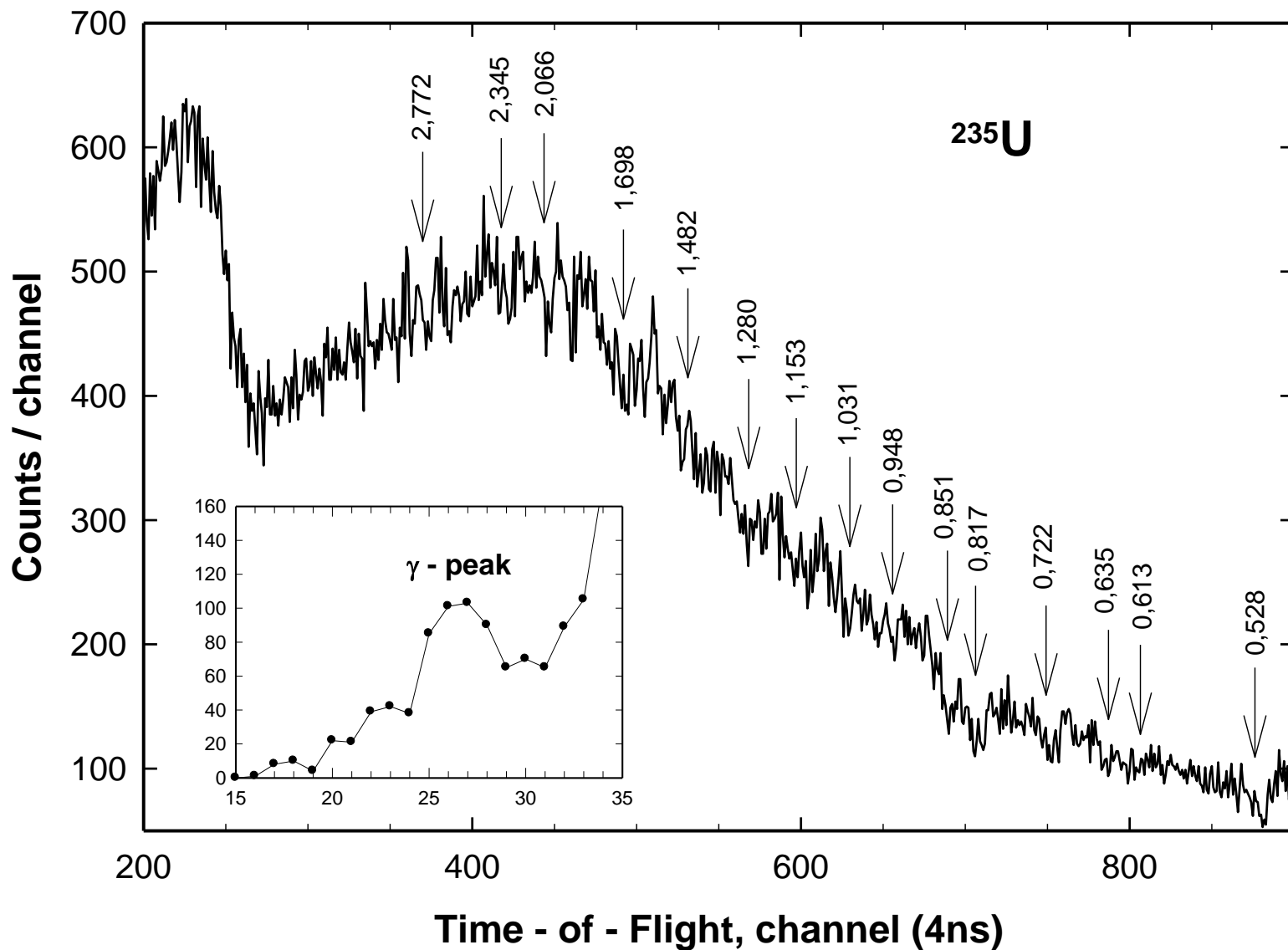
# Internal structure of the Neutron Beam Monitor - FIC with U-235 and U-238 targets



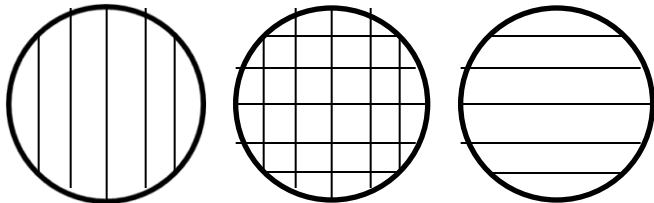
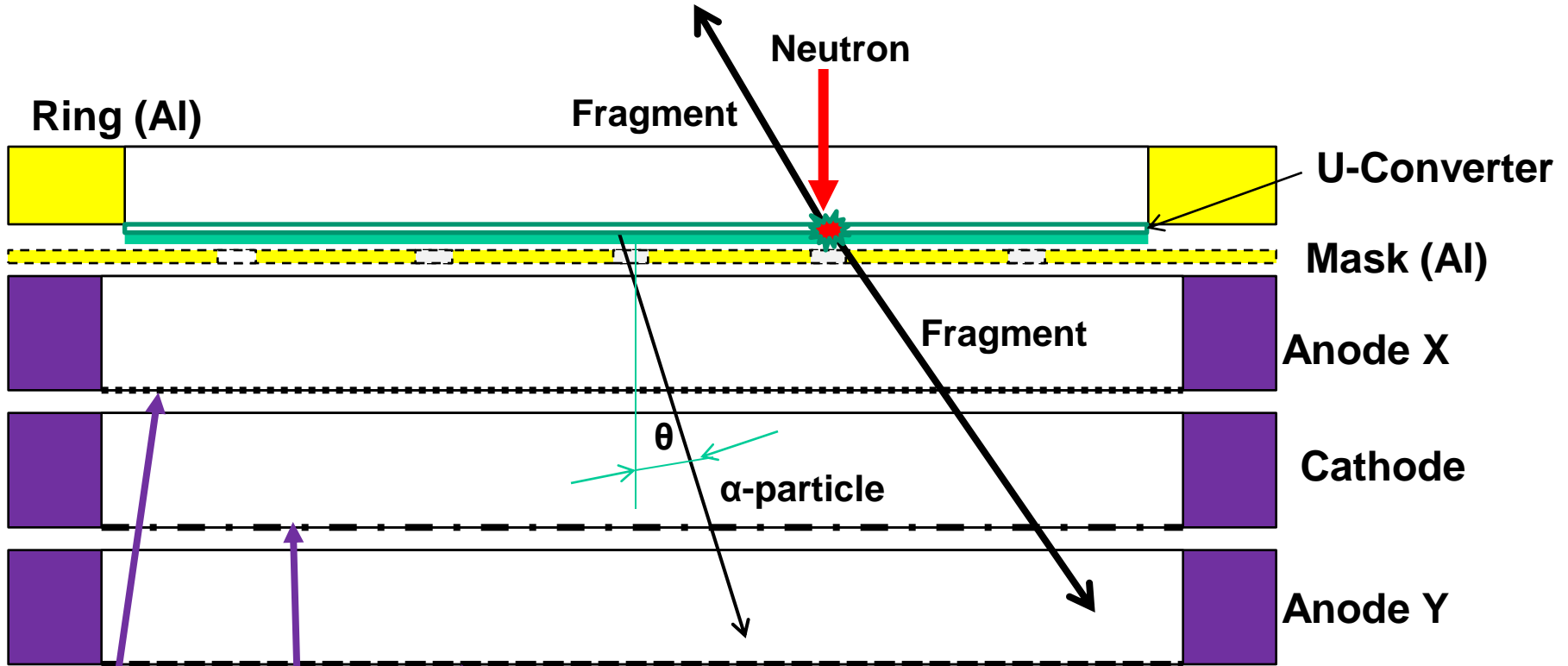
# TOF – Spectra Measured with FIC (Neutron Beam Monitor)



# Fine Structure of FIC-spectrum Used for TOF vs Neutron Energy Calibration



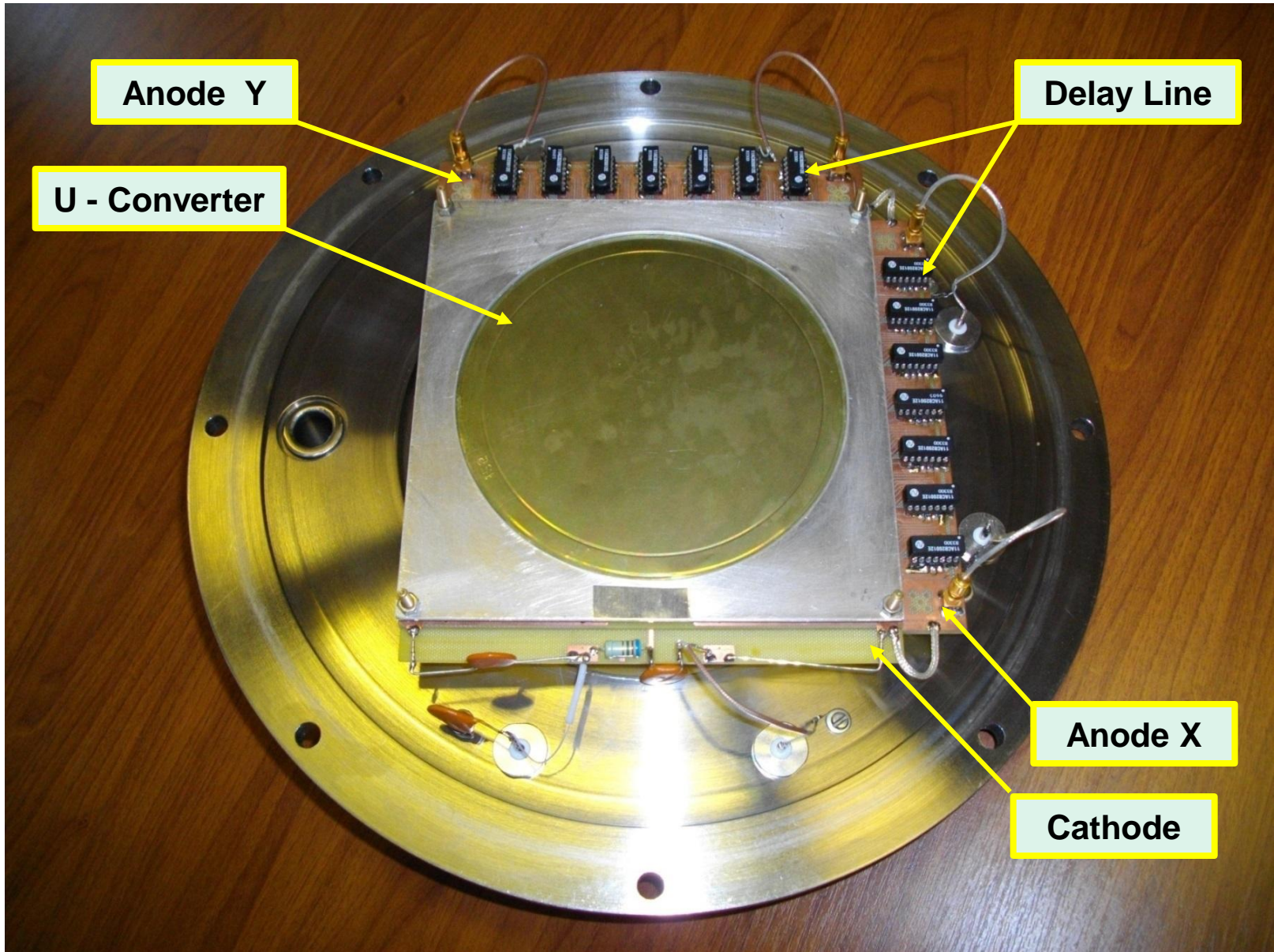
# MWPC – Neutron Beam Profilometer (2D-type MultiWire Proportional Counter)



Anodes / Cathode: 140 W-wires,  $\text{\O}25\mu\text{m}$   
Au-gilded, 1mm step,  
3mm thick fiberglass plastic frame  
Working Gas: isobutene ( $\text{iC}_4\text{H}_{10}$ ), pressure 3-10Torr

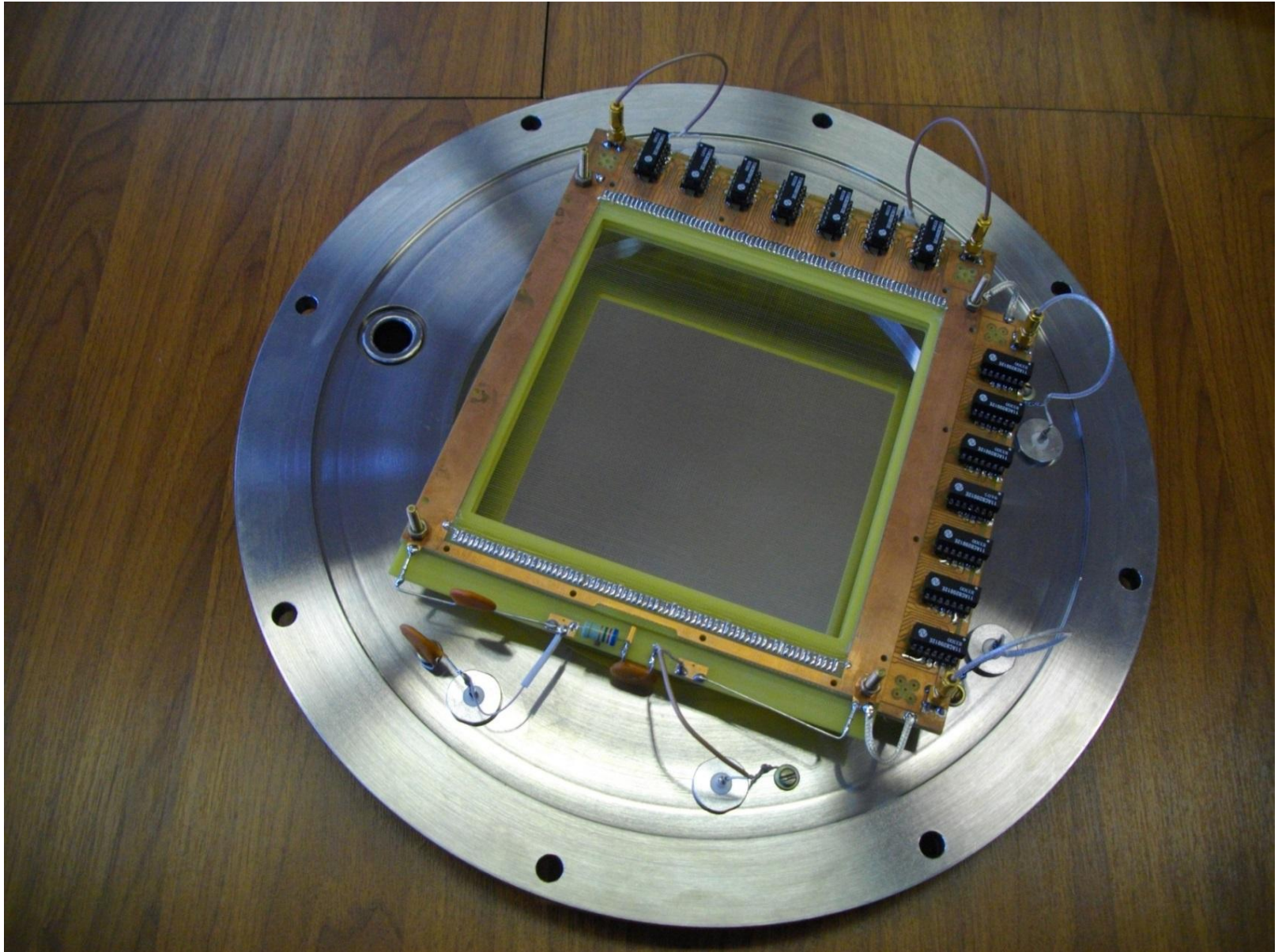


# MWPC – Neutron Beam Profilometer



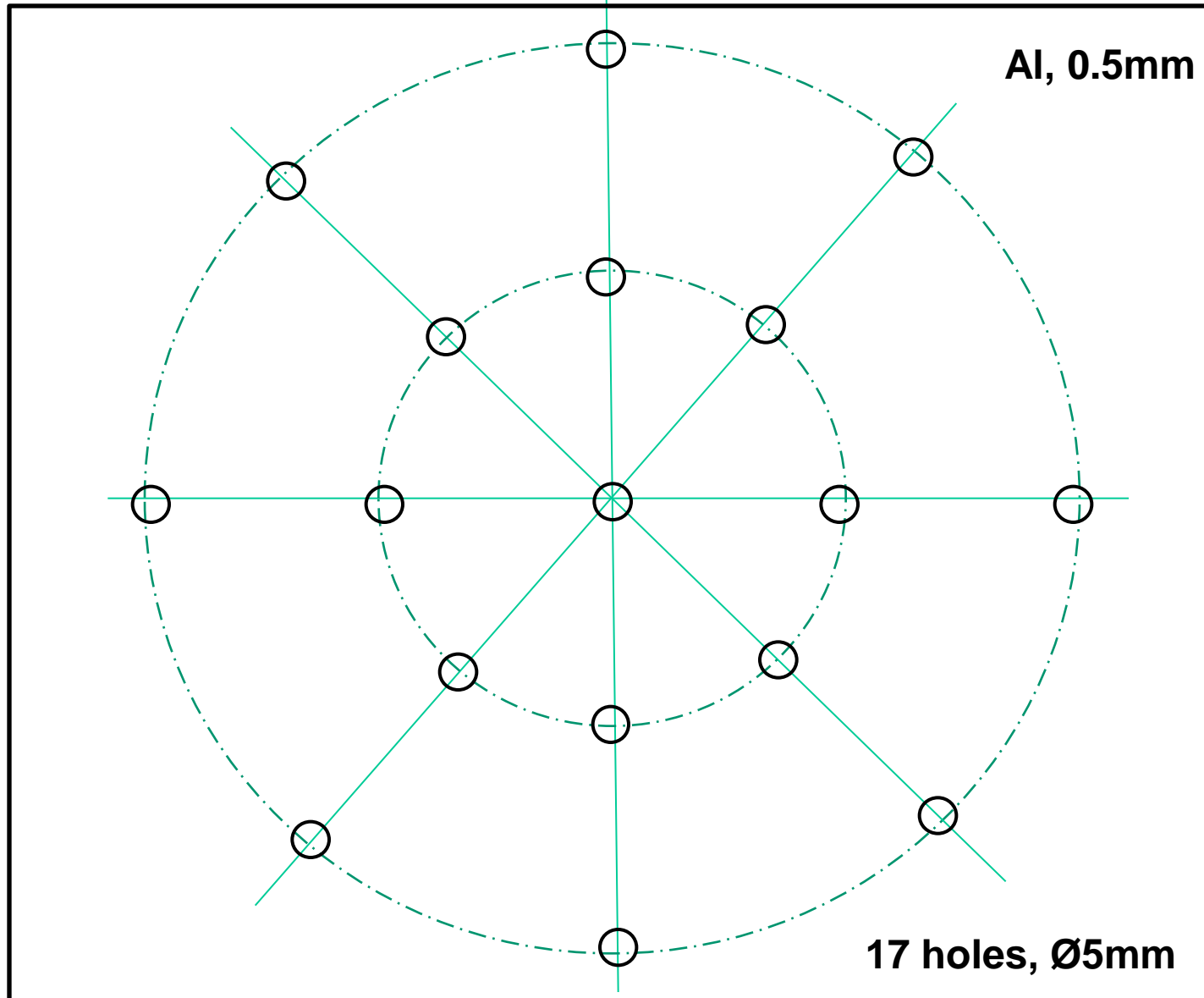


# MWPC – Neutron Beam Profilometer

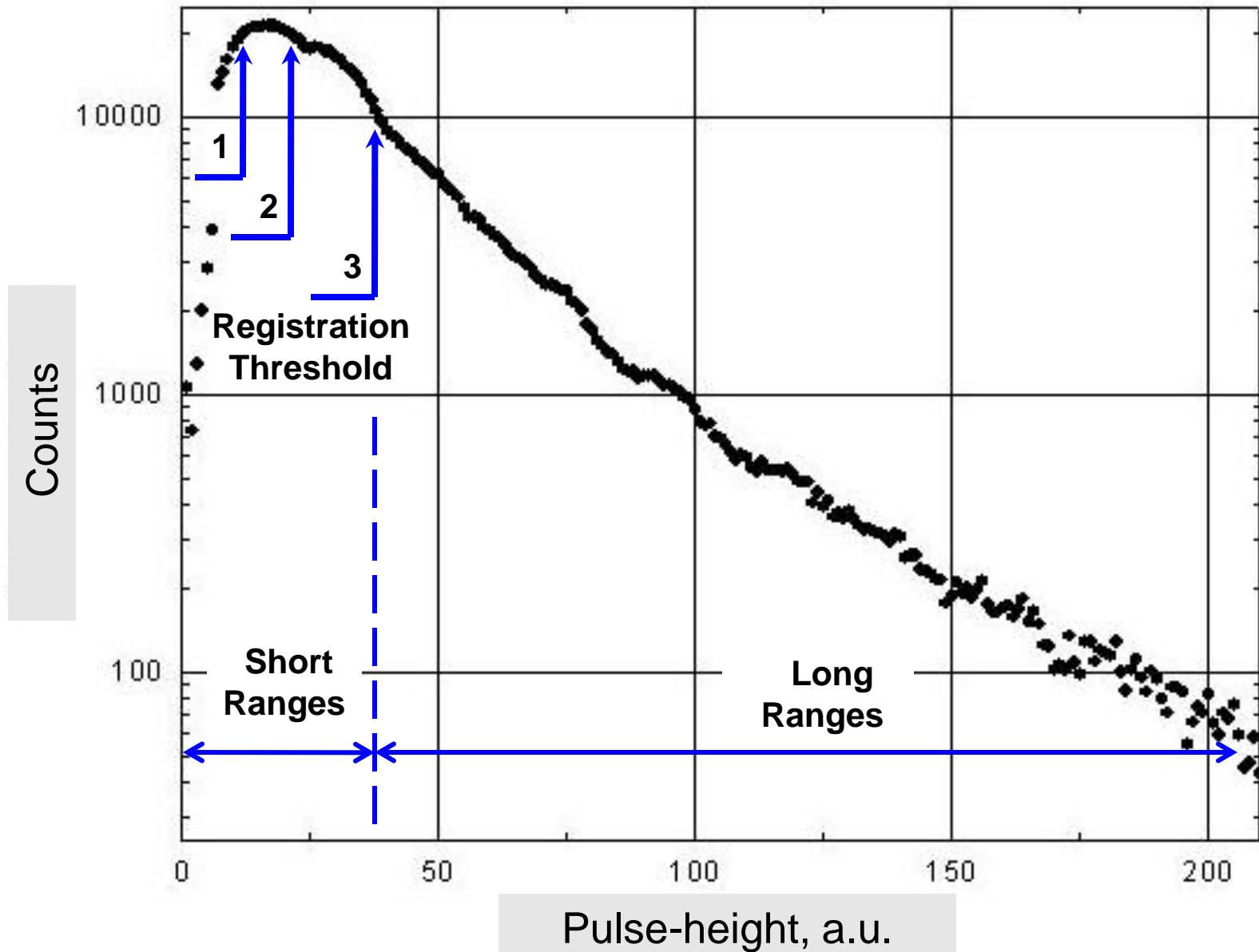




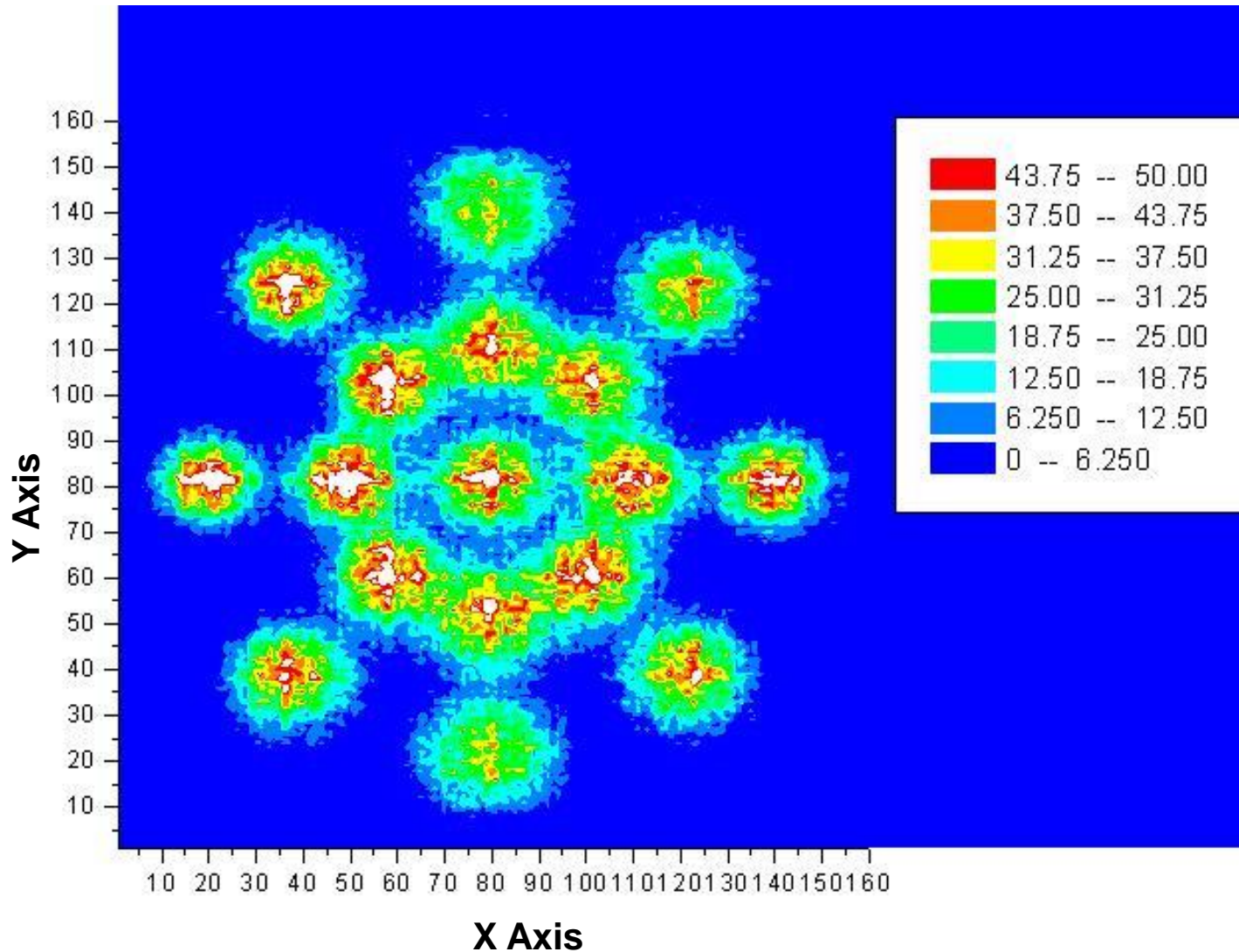
# MWPC – Neutron Beam Profilometer (Mask – Collimator )



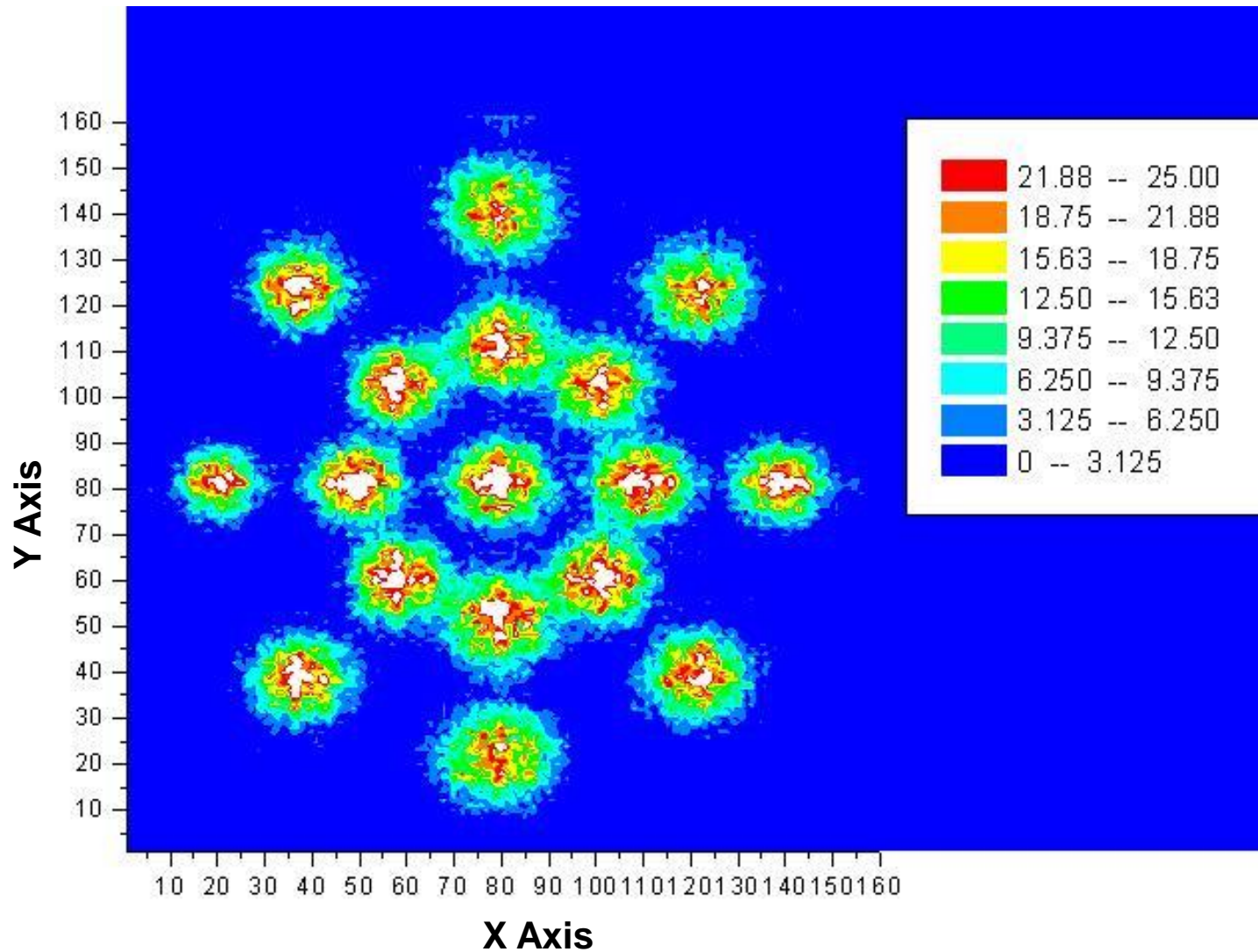
# Cathode Pulse-Height Spectrum ( $\alpha$ -particles)



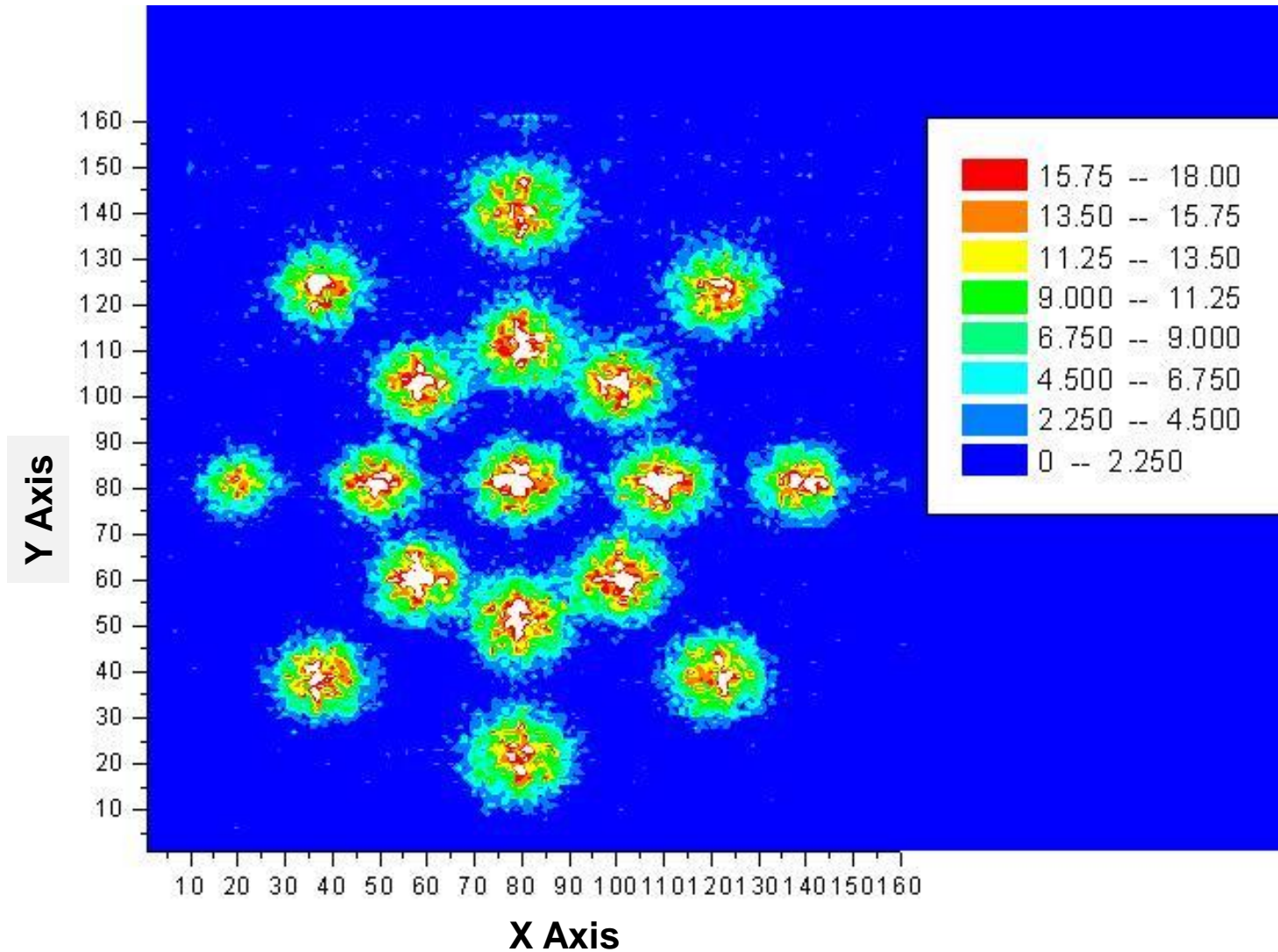
# Anode 2D Pulse-Height Spectrum of $\alpha$ -particles (In Coincidence with Cathode Pulses, Reg. Threshold #3)



# Anode 2D Pulse-Height Spectrum of $\alpha$ -particles (In Coincidence with Cathode Pulses, Reg. Threshold #2)



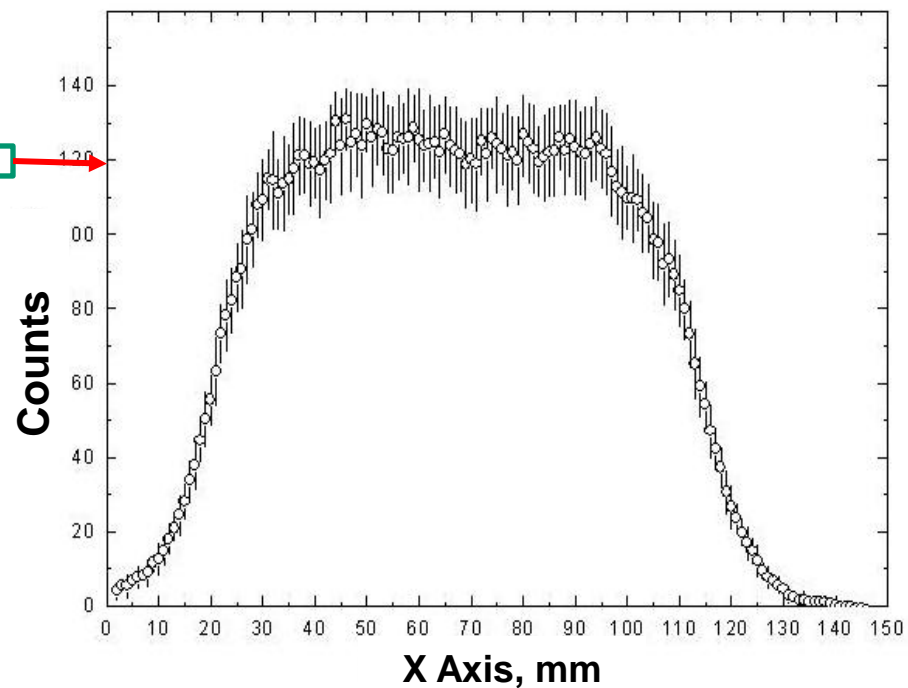
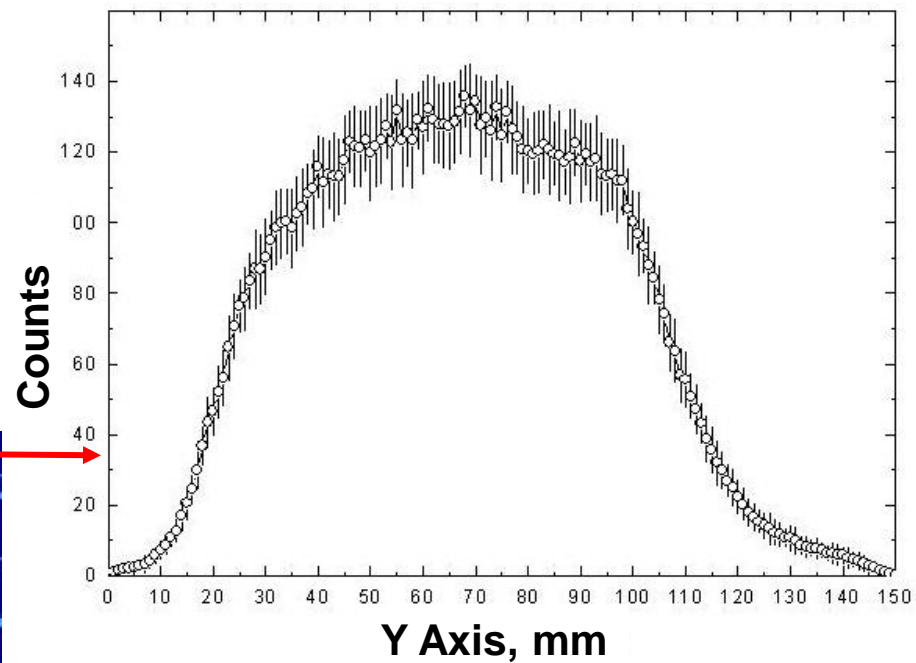
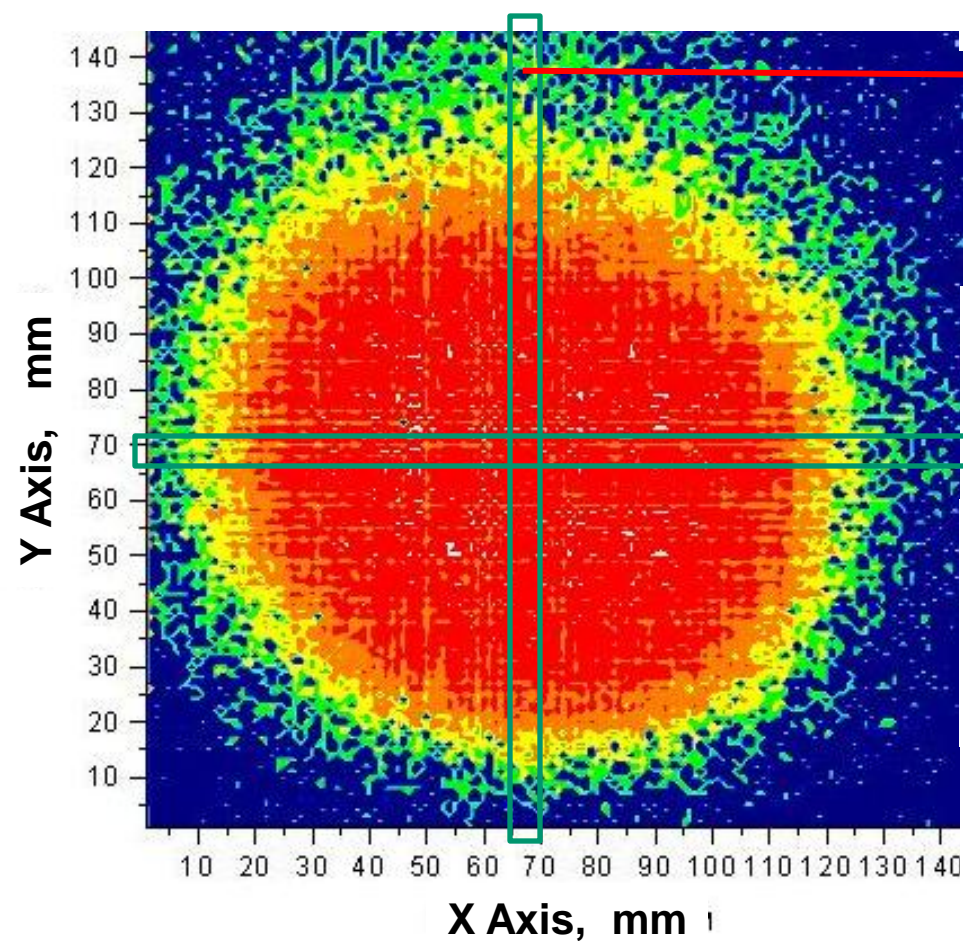
# Anode 2D Pulse-Height Spectrum of $\alpha$ -particles (In Coincidence with Cathode Pulses, Reg. Threshold #1)





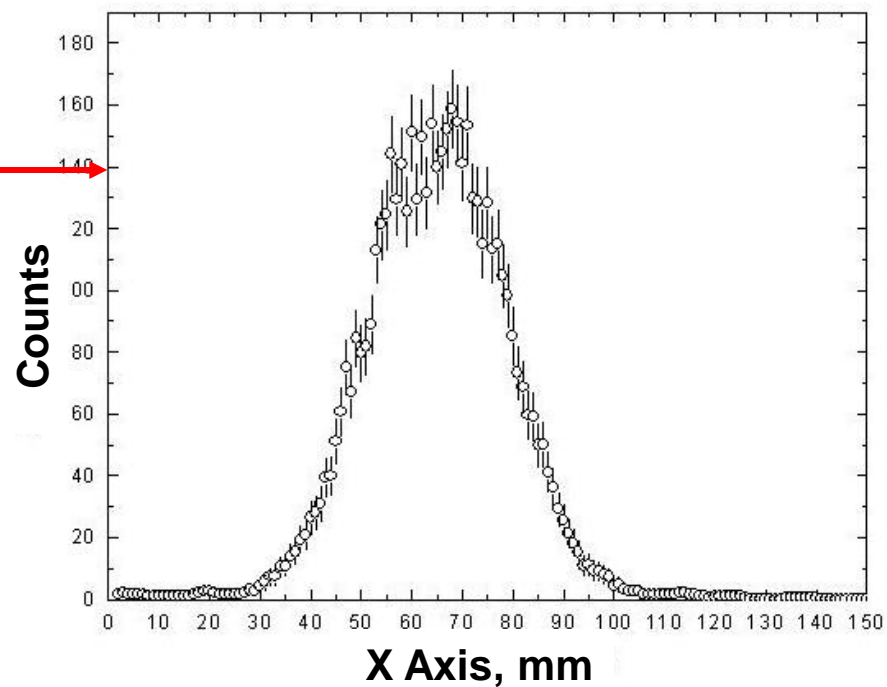
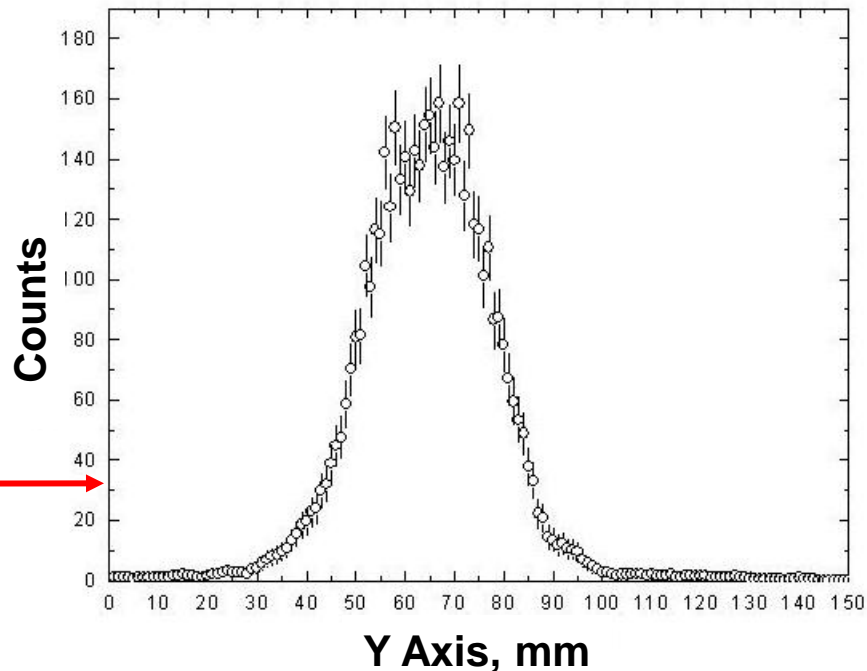
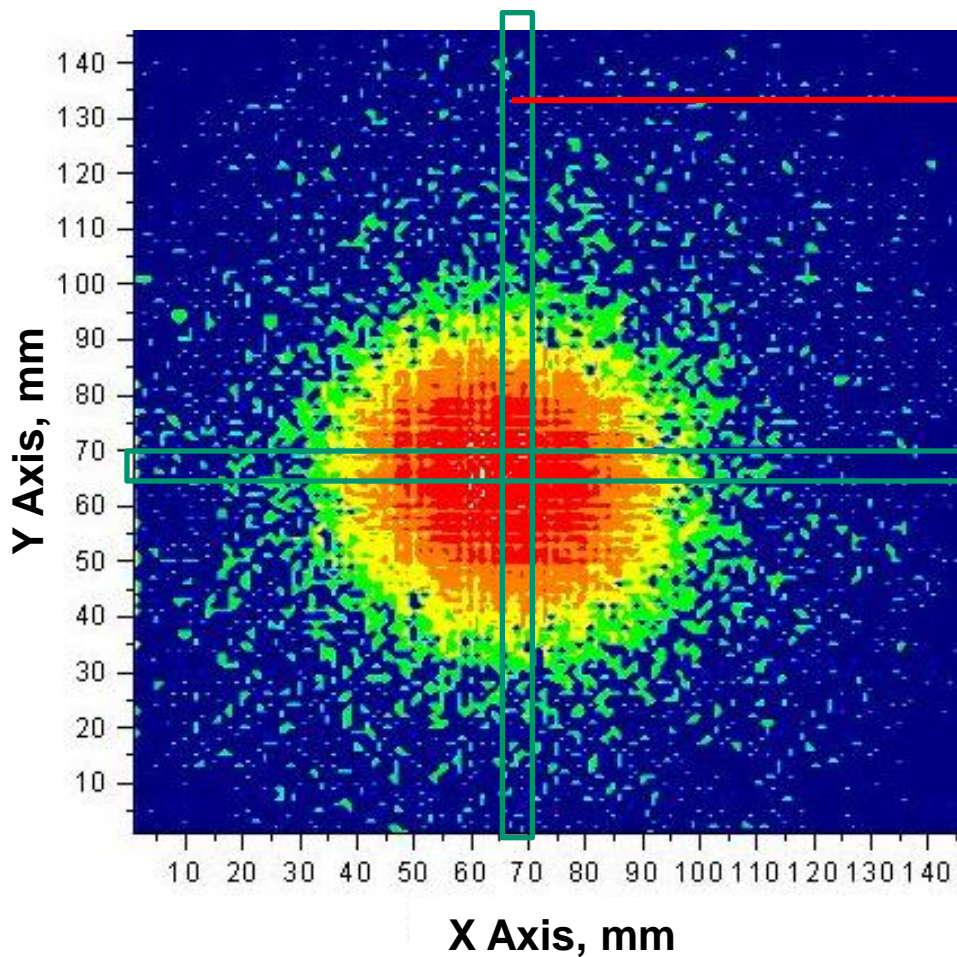
# NEUTRON BEAM PROFILE

Collimator  $\varnothing 96\text{mm}$



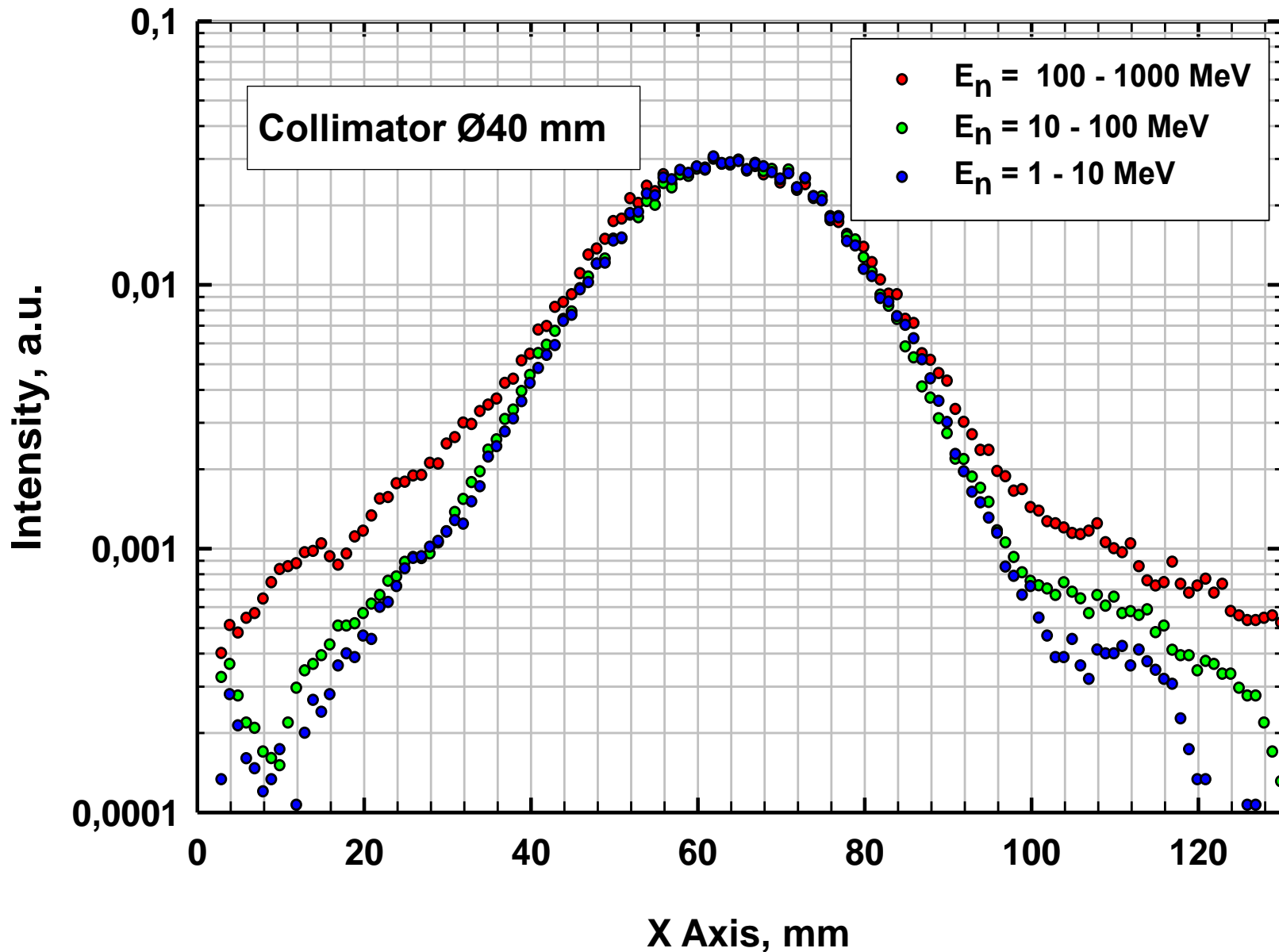
# NEUTRON BEAM PROFILE

Collimator  $\text{\O}40\text{mm}$

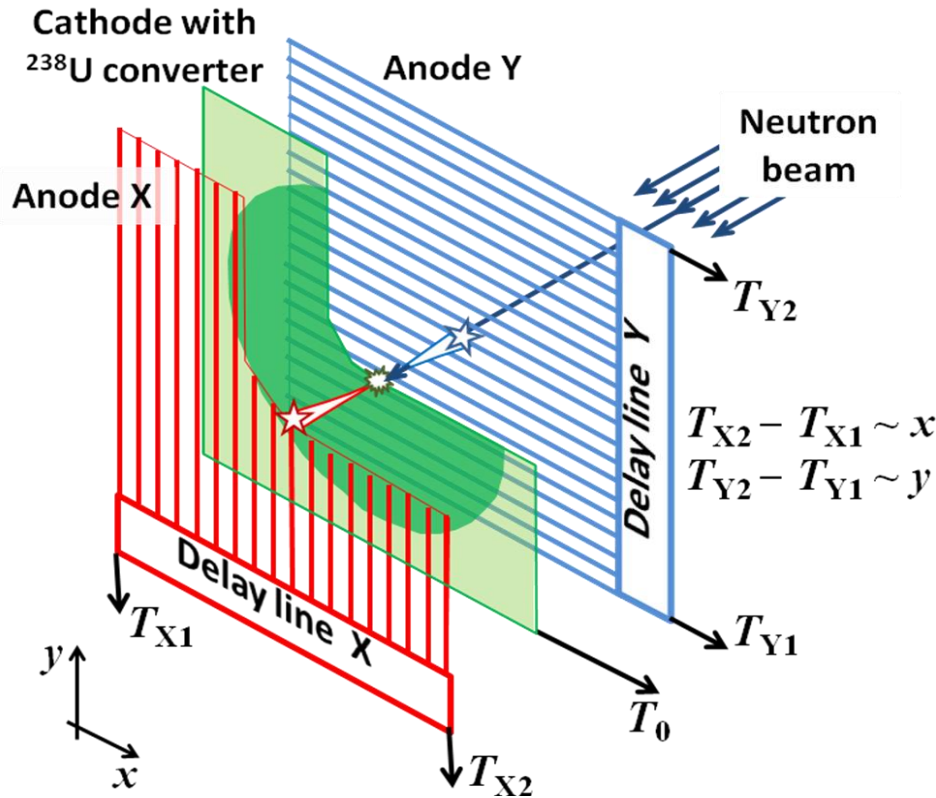




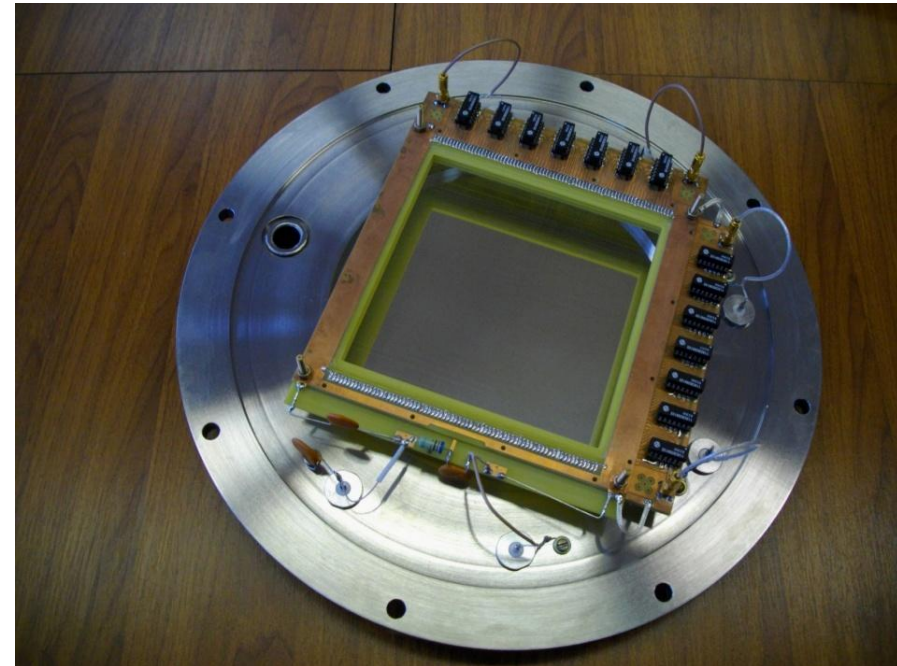
# Neutron Beam Profile vs Neutron Energy



# MWPC – Neutron Beam Profile Meter (position sensitive MultiWire Proportional Counter)

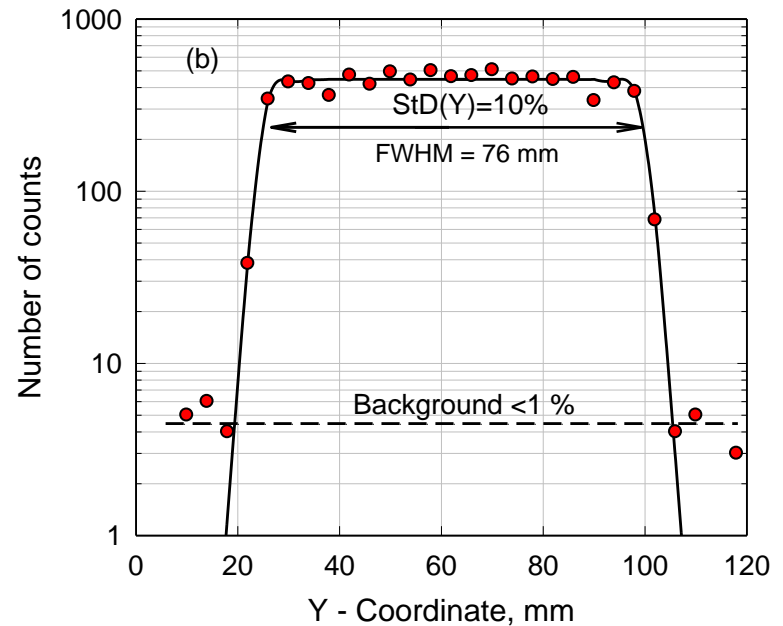
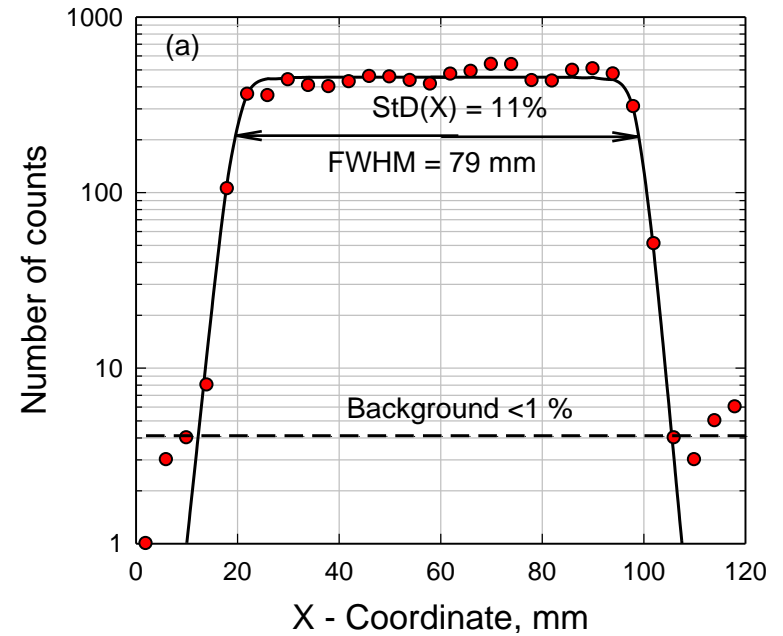
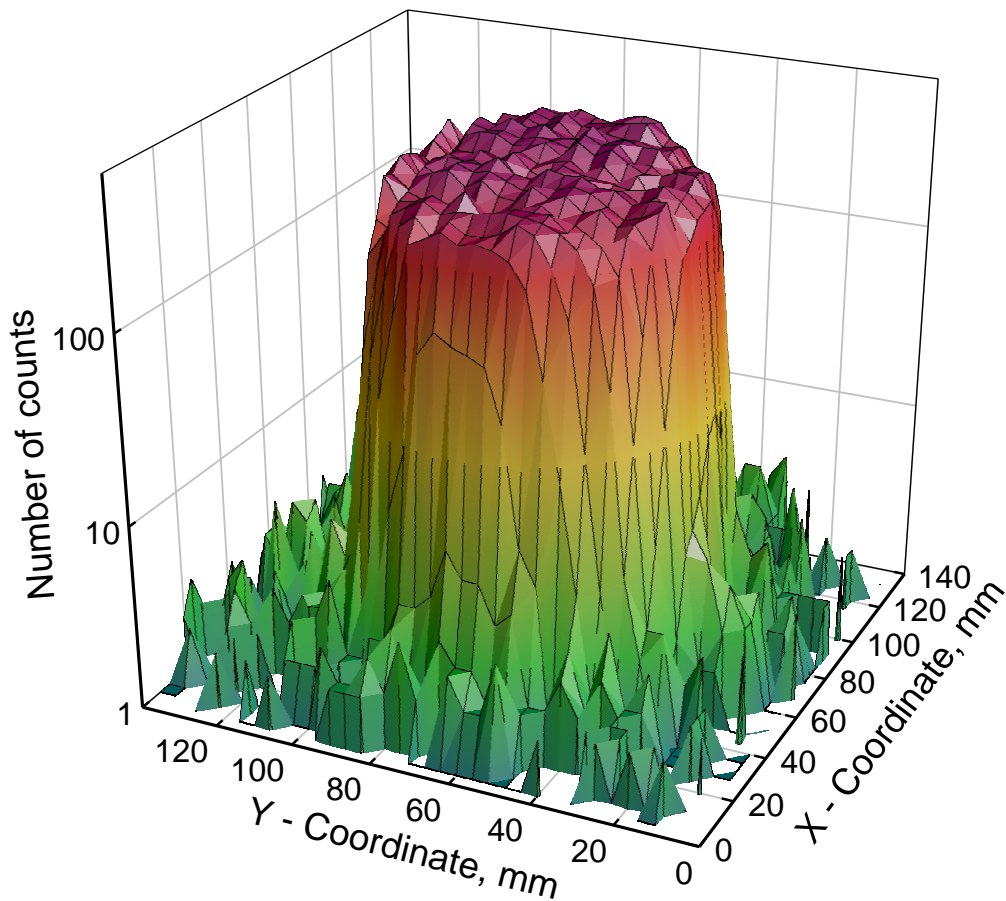


**Size:**  $140 \times 140 \text{ mm}^2$   
**Neutron detection efficiency:**  $3 \cdot 10^{-7}$   
**Spatial resolution:**  
 $2 \text{ mm} < \text{FWHM} < 4 \text{ mm}$



**Anodes:** 140 gilded W-wires,  $\text{Ø}25\mu\text{m}$ , 1 mm step on 3mm thick fiberglass plastic frame  
**Cathode:**  $150 \mu\text{g}/\text{cm}^2$  thick  $^{238}\text{U}$  converter on aluminized  $2 \mu\text{g}$  thick Mylar film  
**Working Gas:** isobutene ( $\text{iC}_4\text{H}_{10}$ ), 6-7 Torr  
**Data read-out:** delay lines, 2 ns/step

# 3D-neutron beam profile, Horizontal (X) and Vertical (Y) beam profiles measured with Ø75 mm beam collimator



# **Comparative Study of Dark Currents in CCD – Matrix Irradiated by PROTONS and NEUTRONS**

CCD (Charge-Coupled Device) - Matrix :

- image sensor Avionic and Space equipment
- commonly used in for coloured and black/white video cameras;

Irradiation of CCD-Matrix by high-energy protons and neutrons leads to:

- overall degradation
- appearance of isolated pixels, the so-called “spikes”:
- “spikes” look as isolated white spots , which lead to the image distortion and subsequent equipment failure;
- example: failure of the navigation system during the process of spaceship docking.

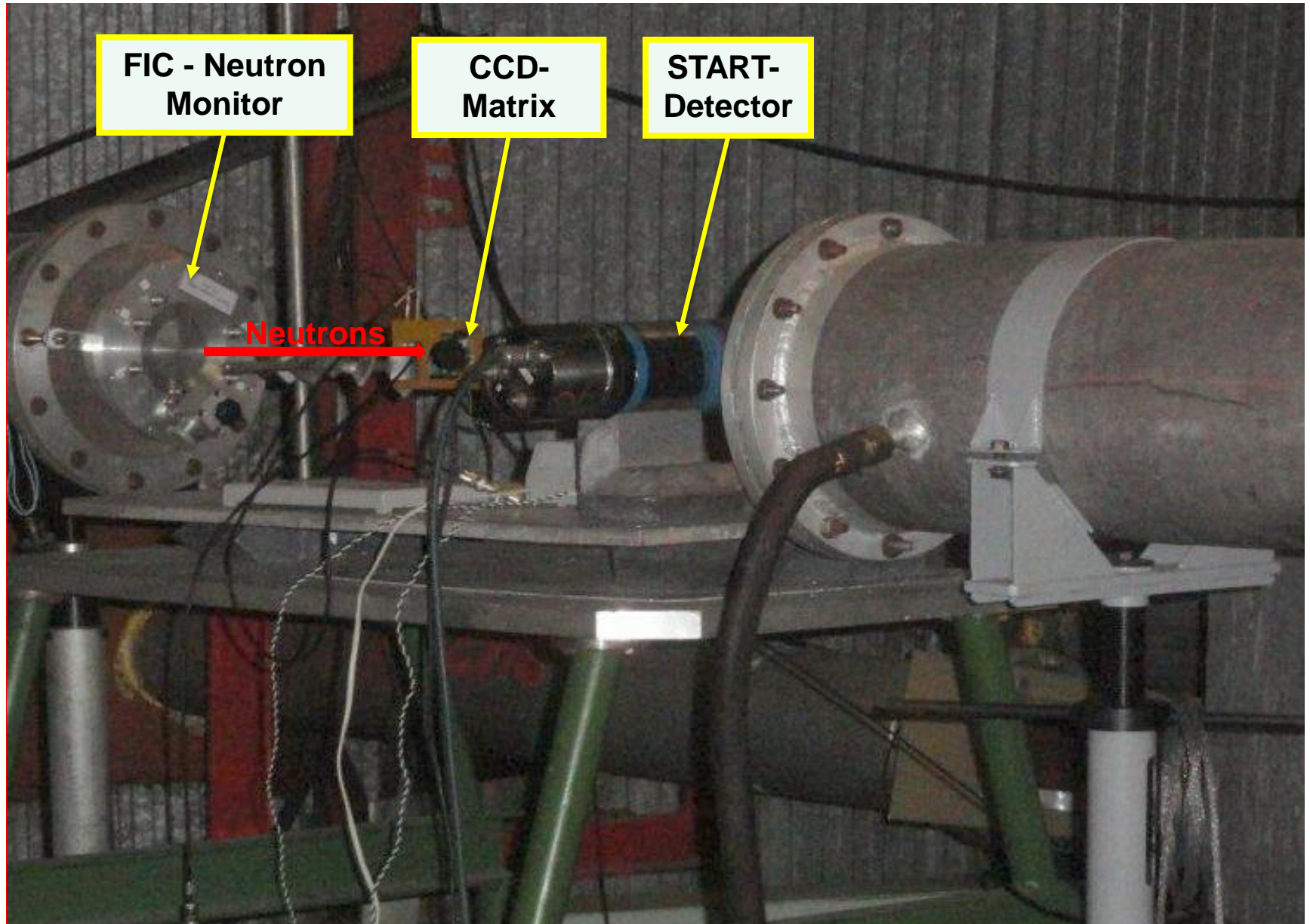
High-priority task: CCD – matrix testing with 1GeV protons and atmospheric-like neutron spectrum (1MeV – 1GeV).

**This is first experiment at the GNEIS (2010)**

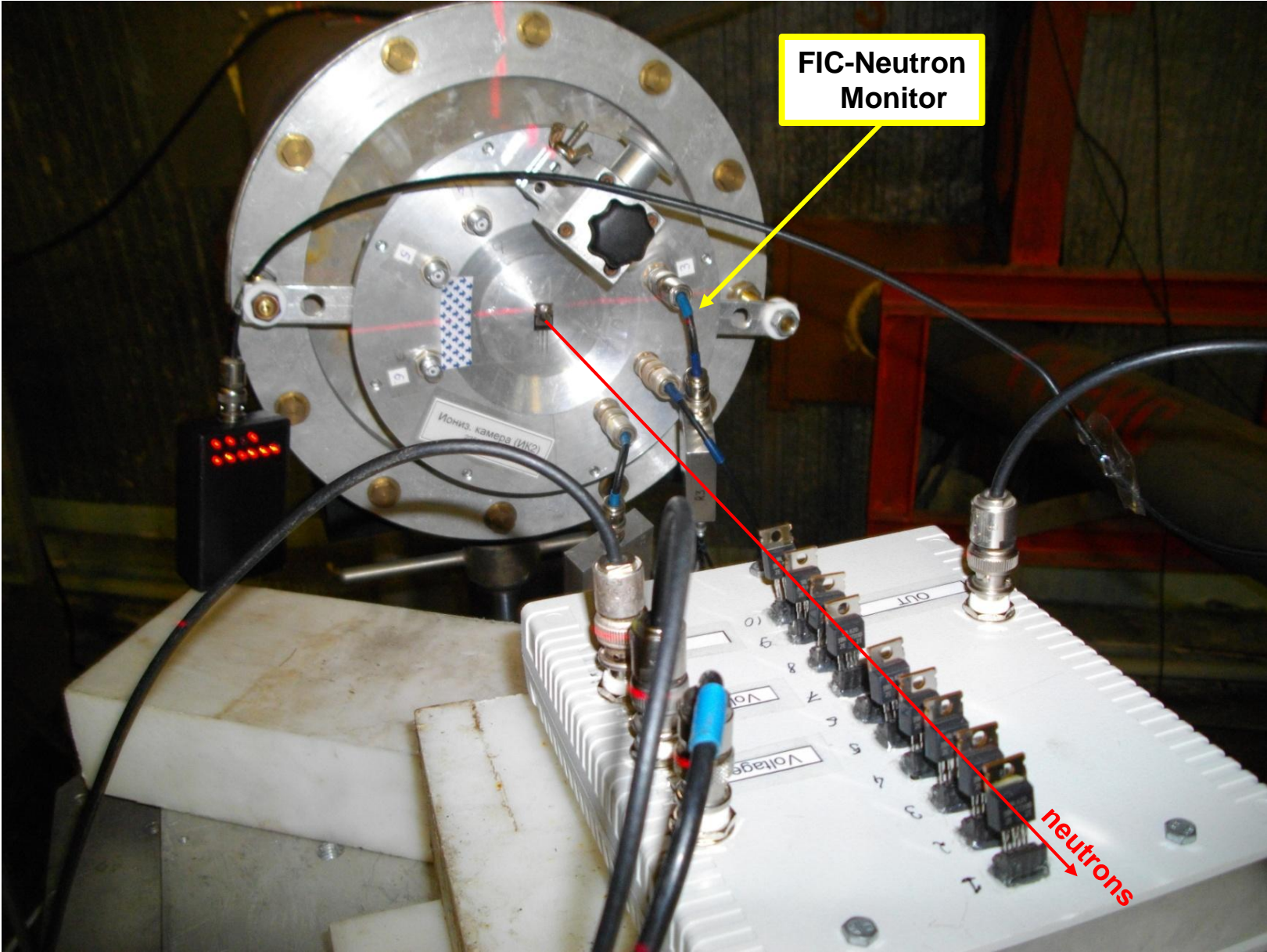
**devoted to the neutron radiation resistance test of electronics.**



## Neutron Irradiation of CCD-Matrix (2010)

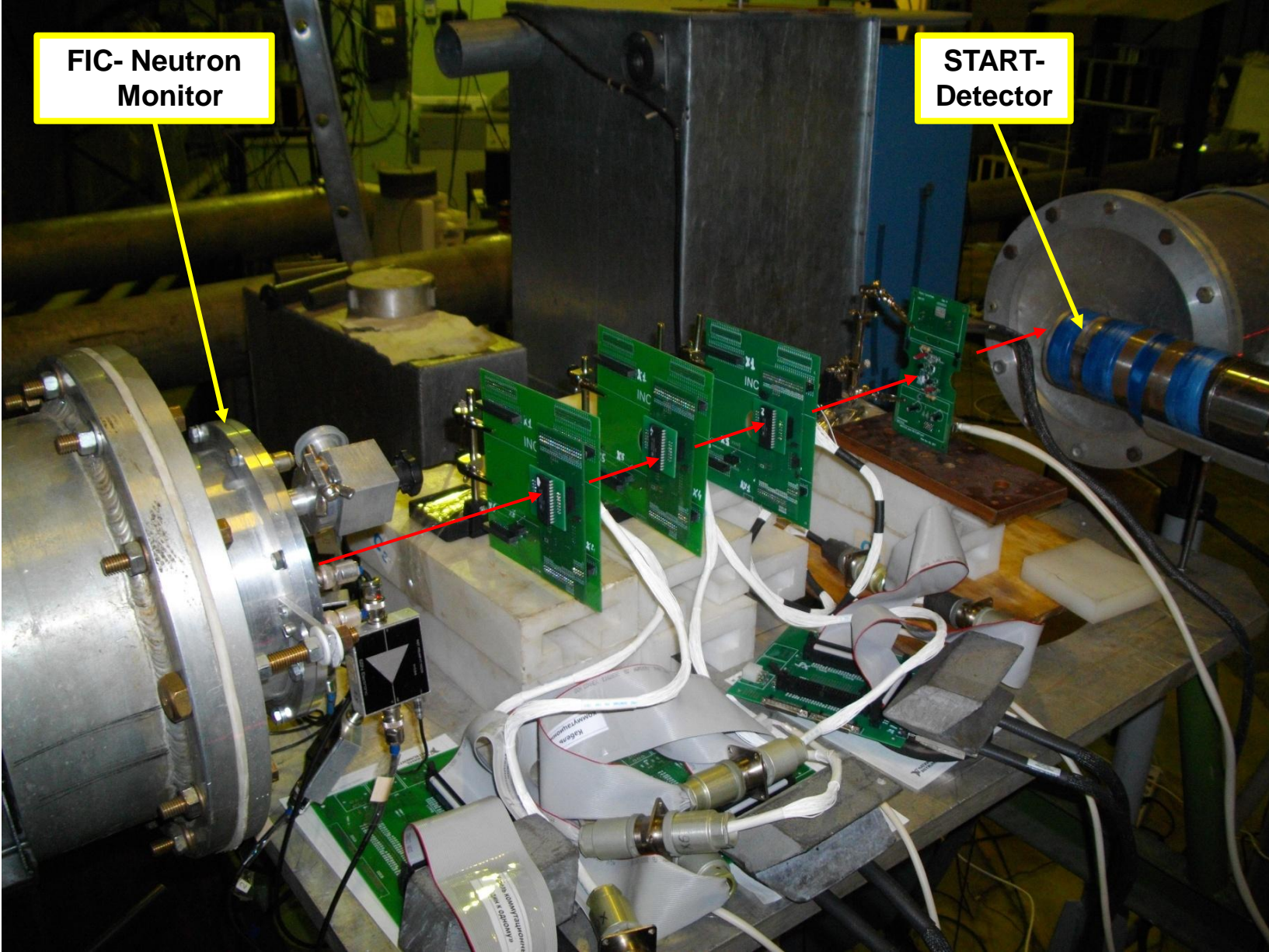


# Neutron Irradiation of MOS - Transistors (2012)



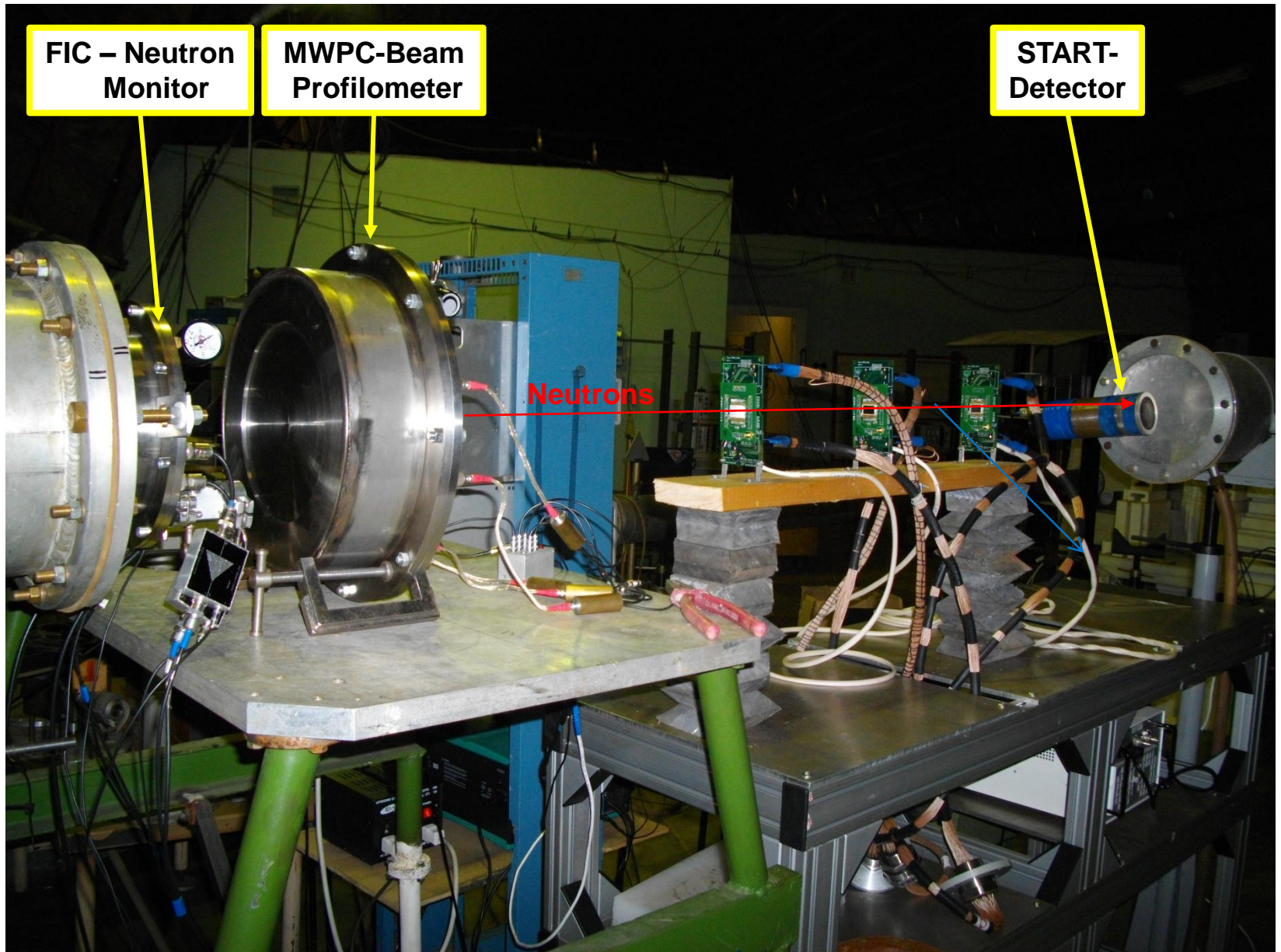


# Neutron Irradiation of SRAM - Chips (2013)

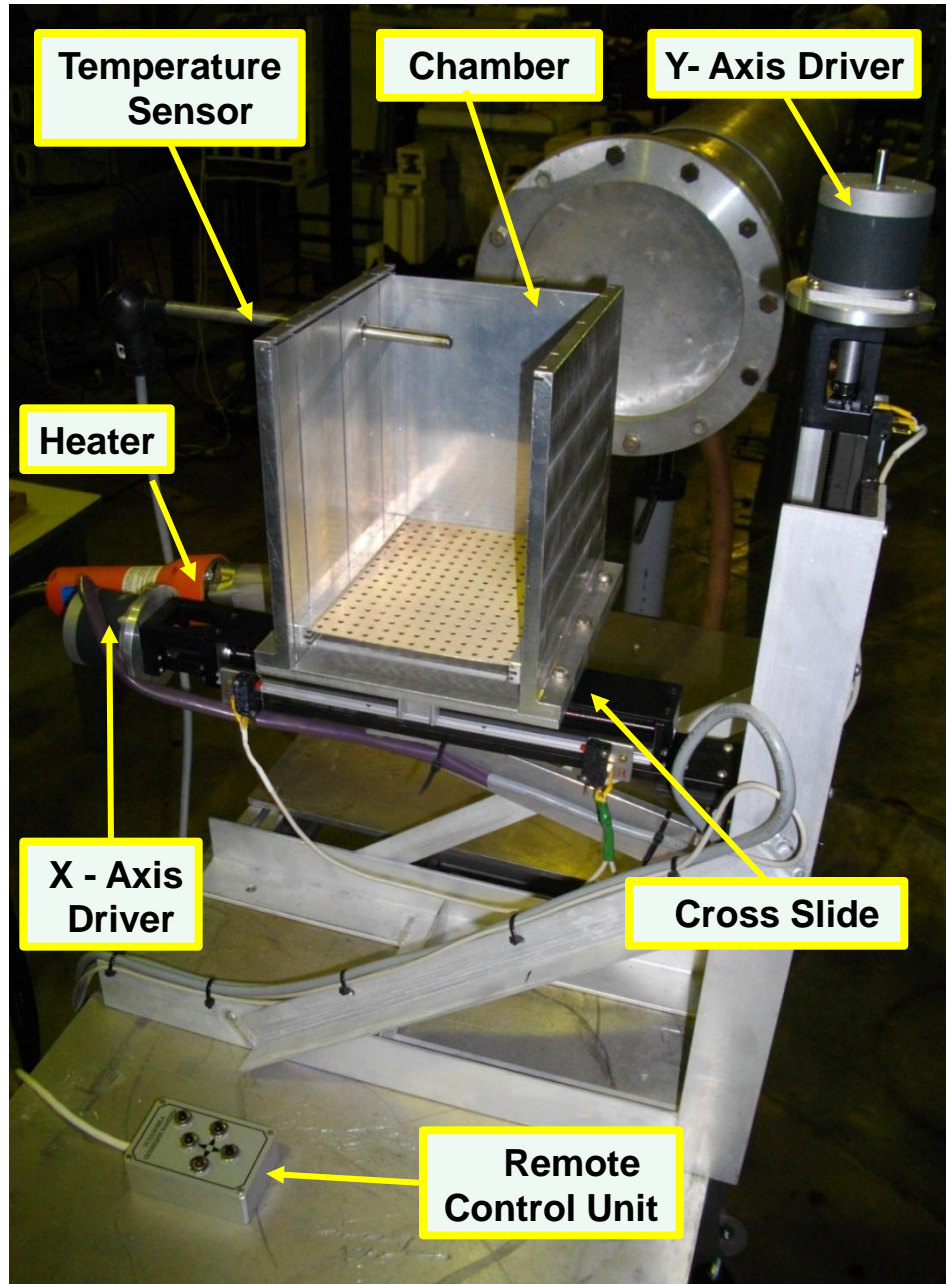




# Neutron Irradiation of SRAM - Chips (2014)



# System for DUT (Device Under Test) Positioning and Heating

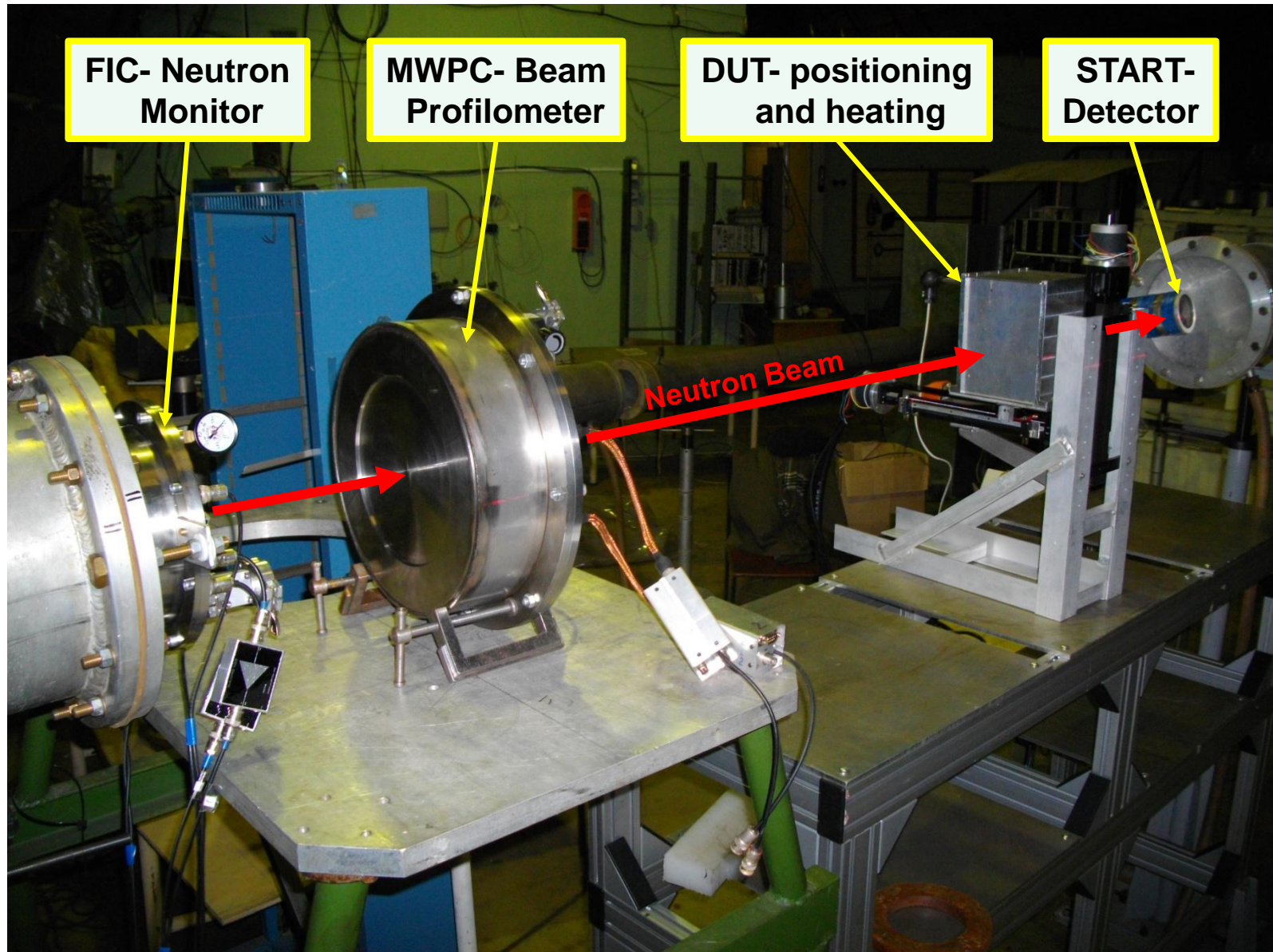


DUT enclosed in the Heating Chamber can be:

- heated, temperature range 20°C – 130°C
- max. heating / cooling time 300 sec (closed chamber) 600 sec (upper cover removed)
- moved along X-Y axes, max. displacement range 200 mm
- max. DUT dimensions 150 mm x 150 mm
- Distant Computer control



# Neutron Testing Facility at GNEIS (2015)



# Results of the SRAM tests carried out at the ISNP facility (2015)

Device type	Fluence*) (neutron / cm <sup>2</sup> )	$\sigma_{\text{seu}}$ (cm <sup>2</sup> / bit)
CY7C1021BN - 15ZSXE	$1.6 \cdot 10^9$	$9.6 \cdot 10^{-15}$
CY62256NLL - 55SNXI	$2.9 \cdot 10^{10}$	$2.2 \cdot 10^{-15}$
UT6264CPCL - 70LL	$1.4 \cdot 10^{10}$	$3.2 \cdot 10^{-14}$
CY61248ELL - 45ZSXA	$2.8 \cdot 10^9$	$8.5 \cdot 10^{-14}$
CY7C1049CV33 - 12ZSXA	$1.4 \cdot 10^9$	$6.6 \cdot 10^{-15}$
CY7C1049DV33 - 10ZSXI	$1.7 \cdot 10^9$	$3.0 \cdot 10^{-15}$

\*)Represented data correspond to neutron fluence  
in the energy range 1-1000 MeV

# CONCLUSION

- at the neutron TOF-facility GNEIS based on the 1 GeV proton synchrocyclotron of the PNPI, it was developed a neutron test facility with atmospheric – like neutron spectrum in energy range 1 – 1000 MeV and integral neutron flux  $4 \cdot 10^5$  n/cm<sup>2</sup>·s;
- our facility enables to carry out accelerated neutron tests of electronic equipment; 1 hour of neutron irradiation at the ISNP/GNEIS is equal to 110 000 hours of natural neutron irradiation at the altitude of 10-12 km and  $4.6 \cdot 10^7$  hours (5250 years) at the sea level;
- during 2010-2015, the neutron irradiation tests of various electronic devices have been done at the ISNP/GNEIS simultaneously with the proton irradiation tests.

**В СОЗДАНИИ НЕЙТРОННОГО ИСПЫТАТЕЛЬНОГО СТЕНДА  
ИСНП/ГНЕЙС  
И ПРОВЕДЕНИИ ИСПЫТАНИЙ  
принимали участие**

- Ускорительный отдел ОПР
- Группа физики деления ядер (ГНЕЙС) ОНИ
- Отдел автоматизации экспериментов на реакторах ОНИ
- Лаборатория кристаллооптики заряженных частиц ОФВЭ
- Отдел трековых детекторов ОФВЭ
- Отдел информационных технологий и автоматизации ОПР
- Цех экспериментального и технологического оборудования
- Лаборатория радиационной физики ОПР

**ОГРОМНАЯ БЛАГОДАРНОСТЬ ВСЕМ!**



**Welcome to NICE House GNEIS in Gatchina!**





# НОВЫЕ ПЕРСПЕКТИВНЫЕ УСТАНОВКИ ДЛЯ ПРОВЕДЕНИЯ ИСПЫТАНИЙ ЭКБ И СИСТЕМ НА НЕЙТРОННЫХ ПУЧКАХ С АТМОСФЕРОПОДОБНЫМ СПЕКТРОМ

## ORNL (Ок-Ридж, США)

- действующий нейтронный источник SNS: протоны 1 ГэВ
- **испытательный стенд HETS (High-Energy Neutron Test Station)**
- ЭКБ: сечение пучка 20см x 20см, поток нейтронов  $10^4 - 10^7$  н/см<sup>2</sup>/сек
- блоки ЭО: сечение пучка 1м x 2м, поток нейтронов  $10^2 - 10^4$  н/см<sup>2</sup>/сек
- стоимость проекта – до 100 млн USD
- срок создания – до 5 лет

## RAL (Резерфордская Лаборатория, Чилтон, Великобритания)

- действующий нейтронный источник ISIS: протоны 800 МэВ, W/Та мишень
- действующий испытательный стенд VESUVIO
- **испытательный стенд ChipIR (Chip Irradiation)**
- ЭКБ: сечение пучка 20см x 20см, поток нейтронов  $10^4 - 10^7$  н/см<sup>2</sup>/сек
- блоки ЭО: сечение пучка 1м x 1м, поток нейтронов  $\leq 10^7$  н/см<sup>2</sup>/сек
- стоимость проекта – 15 млн фунтов стерлингов
- установка создана, находится в процессе аттестации и лицензирования

## CIP (Пекин, КНР)

- нейтронный источник CSNS: протоны 1.6 ГэВ, 25 Гц, 500 кВт, W/Та мишень
- **испытательный стенд NIS (Neutron Irradiation Spectrometer)**
- ЭКБ: поток нейтронов до  $2.3 \times 10^6$  н/см<sup>2</sup>/сек
- начало работы – 2018